

# Nanostencil project (FET-Open project)

## A brief review of progress

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Dr. Santiago Olaizola (CEIT-IK4), Prof. Dr. Erkki Levänen (Tampere University), Prof. Dayou Li (U. Bedfordshire, Dr. Hani Abou Hadba/Andreas Börner (Innolas Laser) and colleagues

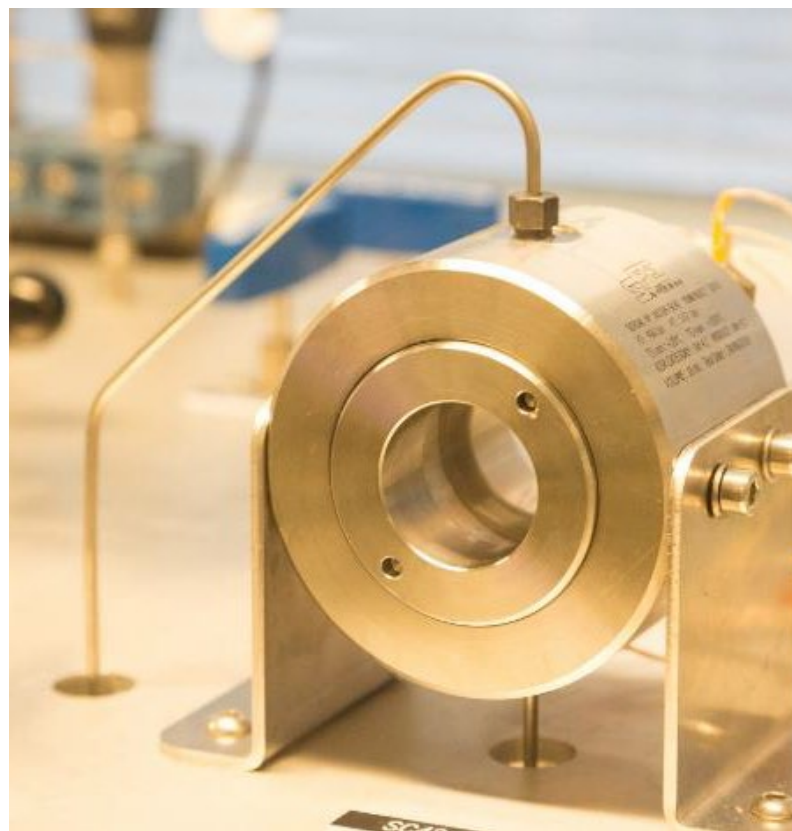
[www.nanostencil-eu.com](http://www.nanostencil-eu.com)

# Nanoscale self-assembled epitaxial nucleation controlled by interference lithography

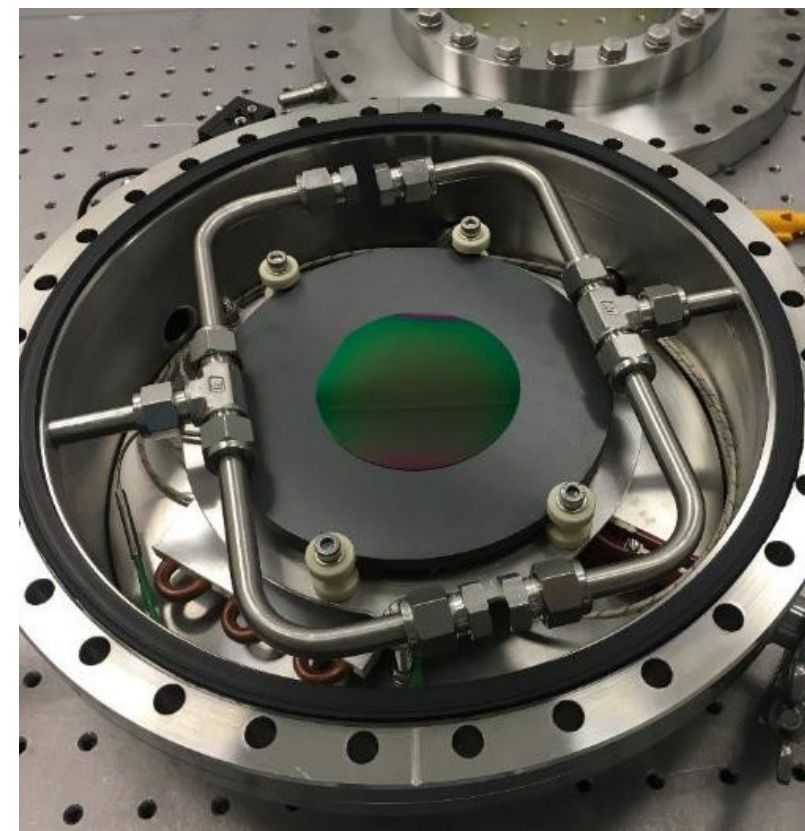
- Aim is to produce dense arrays of nanostructures by performing in-situ laser interference during materials synthesis
- **DLIPS with surface reaction (low energy  $\sim 10$ 's  $\text{mJ}/\text{cm}^{-2}$ )**
- Laser interference periodic patterning via ablation or reaction of materials is well established. We want to use laser interference to form the structures in the first place
- Wish to demonstrate this across several diverse materials systems with device outputs in electronics, photonics, sensing, biomedicine etc



III-V MBE



scCO<sub>2</sub> oxidation



ZnO CVD

Three different materials approaches: three different reactors

# Multi beam Laser Interference Lithography

University of Bedfordshire  
+ other partners

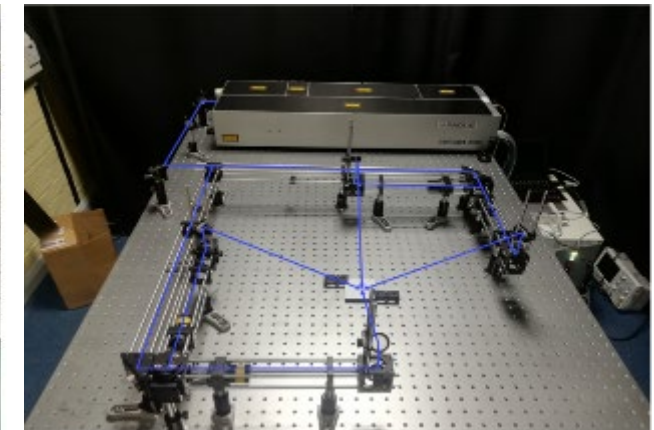
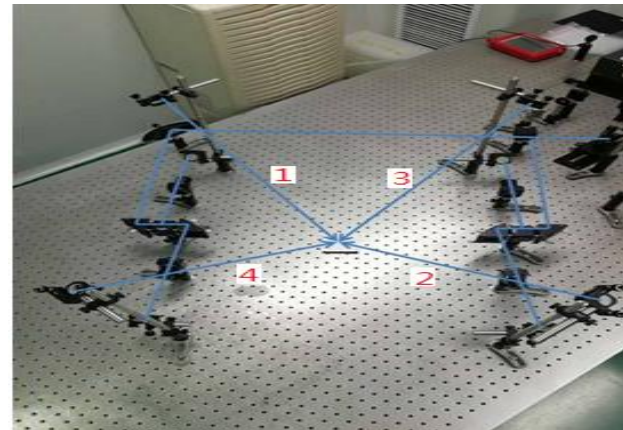
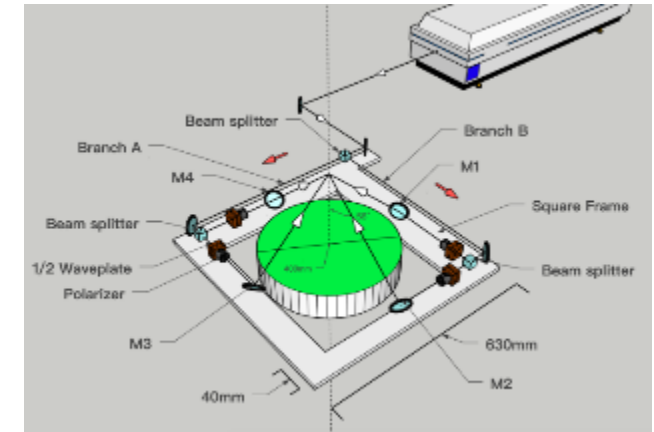
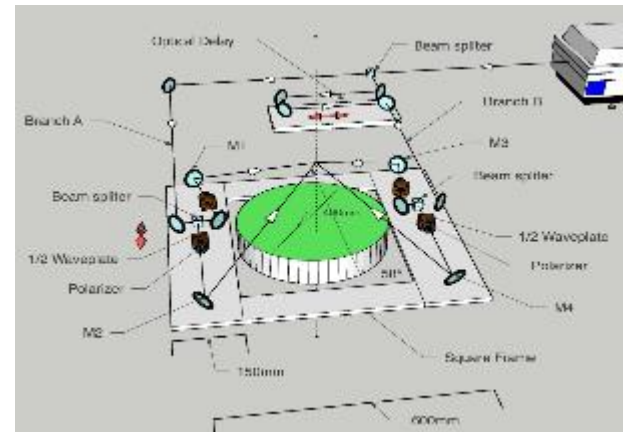
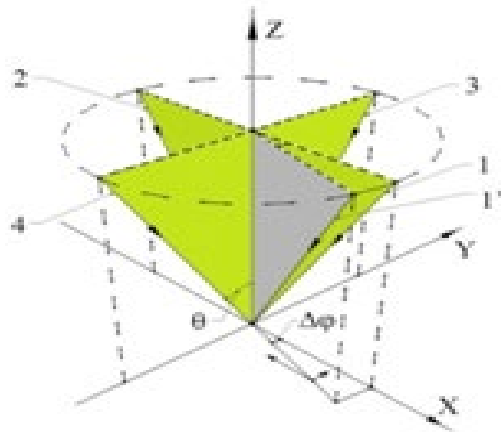


# LIL sub-system design and experimental examination

Two versions of optical design and experimental prototype for MBE Chamber

**Key factors** of LIL should be controlled:

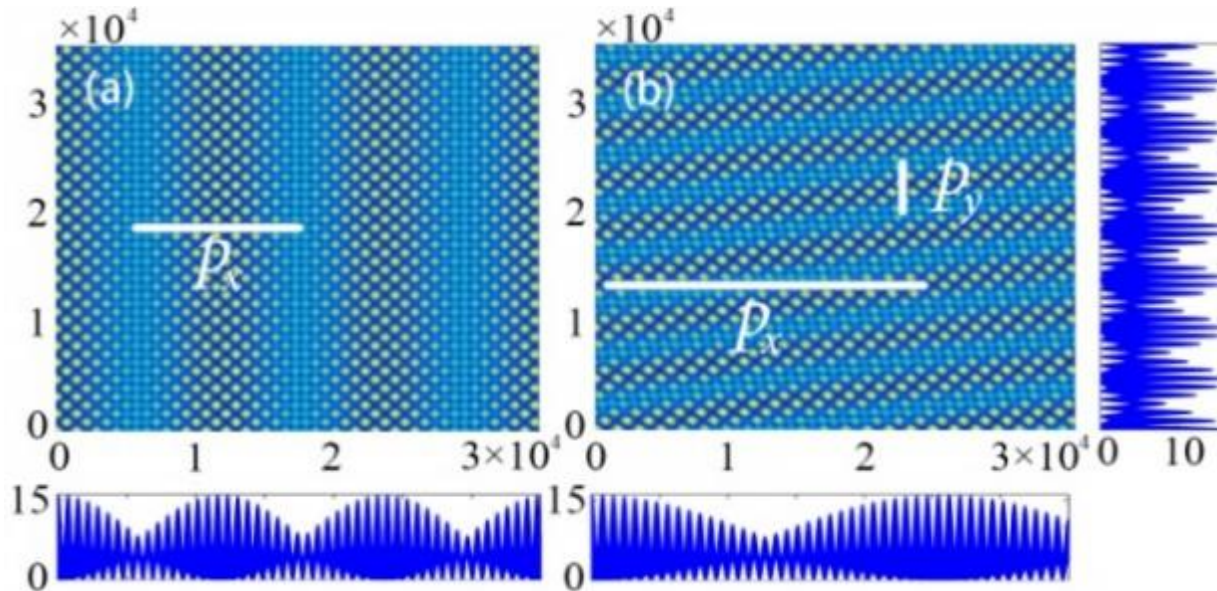
1. Equal optical length;
2. Pointing ( incident and azimuth angle );
3. Polarization combination;
4. Energy density distribution at the superposition area.



# Simulation analysis of the factors to the interference pattern formation

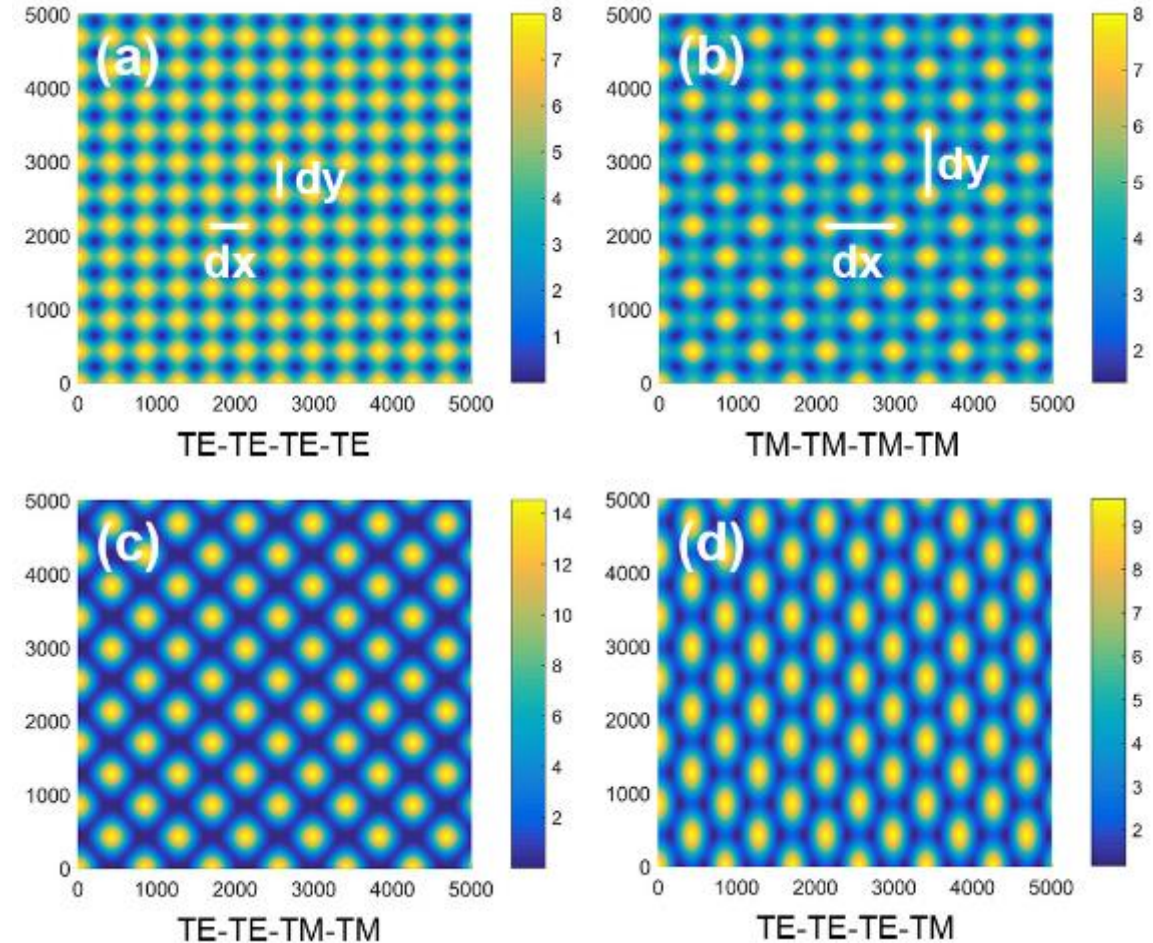


## Initial angle offset affects the Four-beam LIL patterns



- (a) The incident angle is adjusted a tiny angle offset and the figure below is the intensity profile in the X-direction.
- (b) The intensity modulation in two direction due to the tiny azimuth angle offset of one beam )

## The effect of Polarization





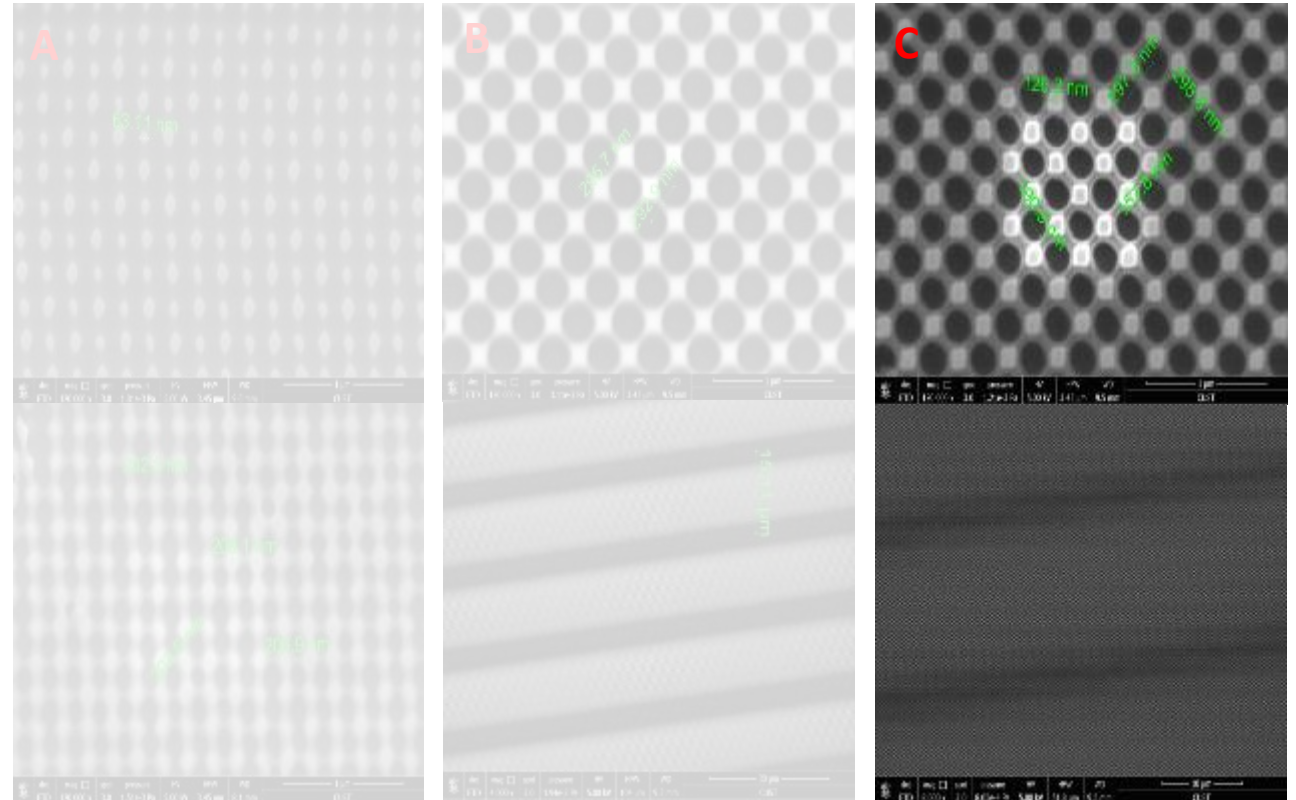
# Experimental photoresist tests

The LIL design and examination setup as show in previous slides, the incident angle is  $58^\circ$ . The results are all obtained from positive photoresist.

The TE-TE-TE-TE polarization combination result as show in Figure A, period is about 200nm.

Figure B is the TE-TE-TM-TM combination result. Significant intensity modulation as show below generated by the initial incident and azimuth angle offset in this mode.

Figure C is the TE-TE-TE-TM combination result, this combination could be a good choice for its relatively high contrast and slightly modulation.

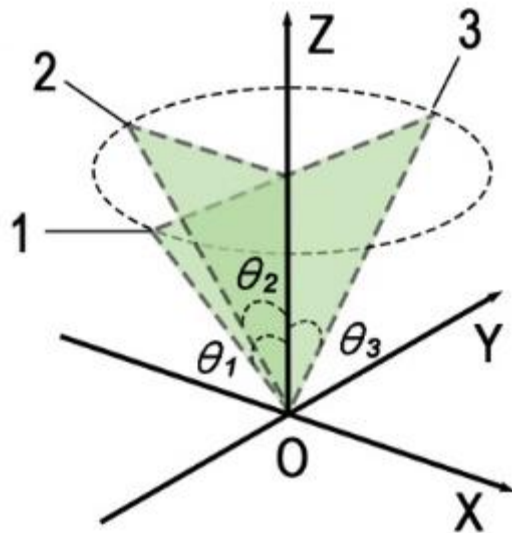


# Asymmetric three-beam LIL design and experimental examination

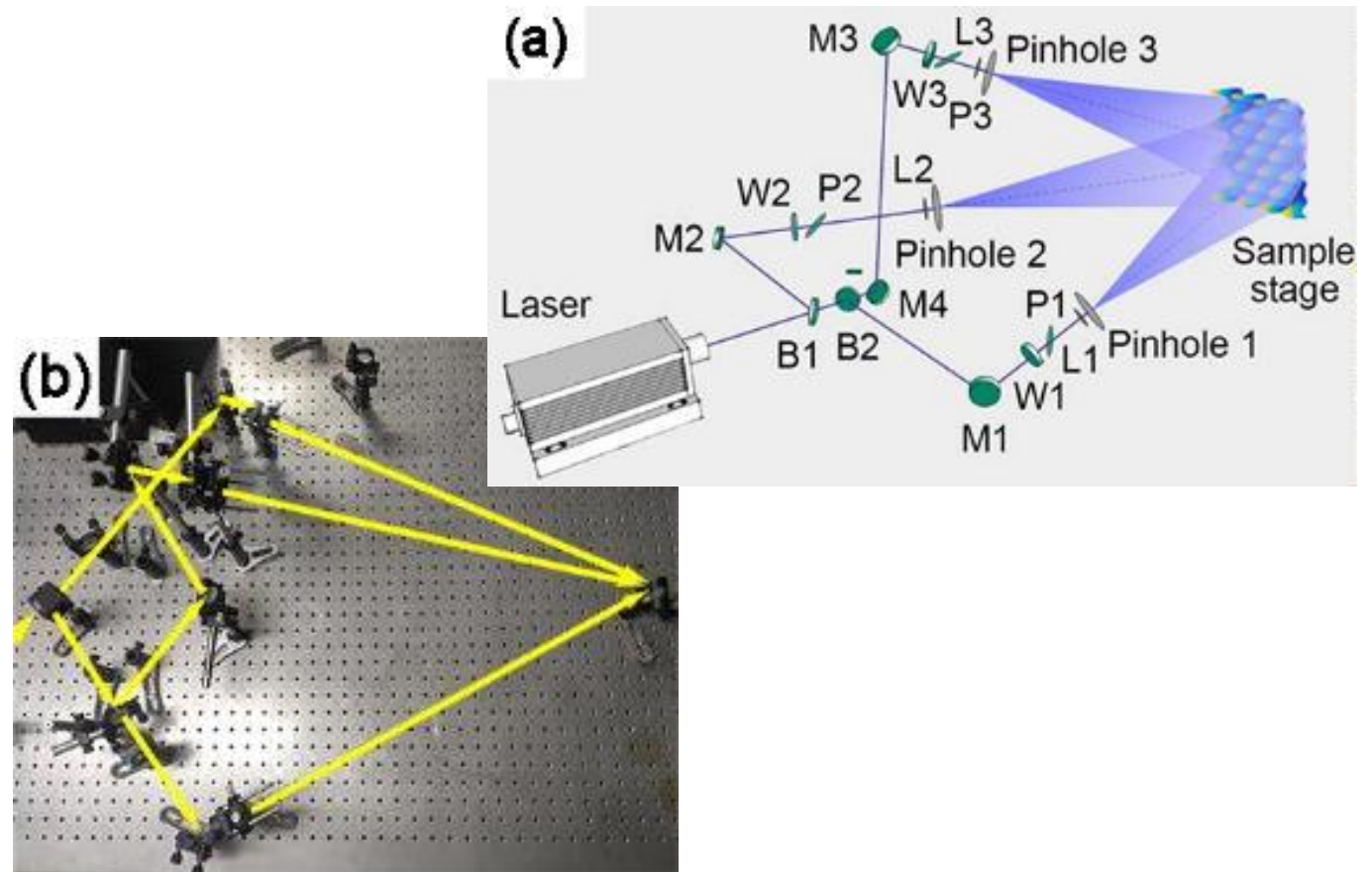
Configurations of the asymmetrical three-beam interference:

(a) Azimuthal angles:  $0^\circ$ ,  $90^\circ$ , and  $180^\circ$ ;

(b) Polarization mode: TE-TM-TE or TM-TE-TM.



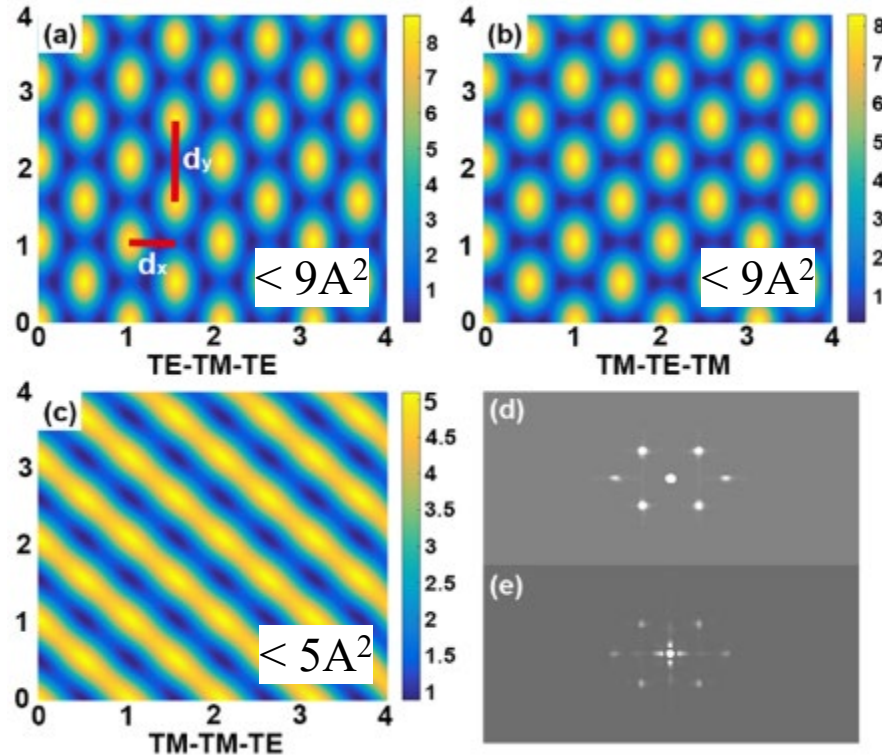
Optical design (a) and asymmetric three-beam LIL system (b)



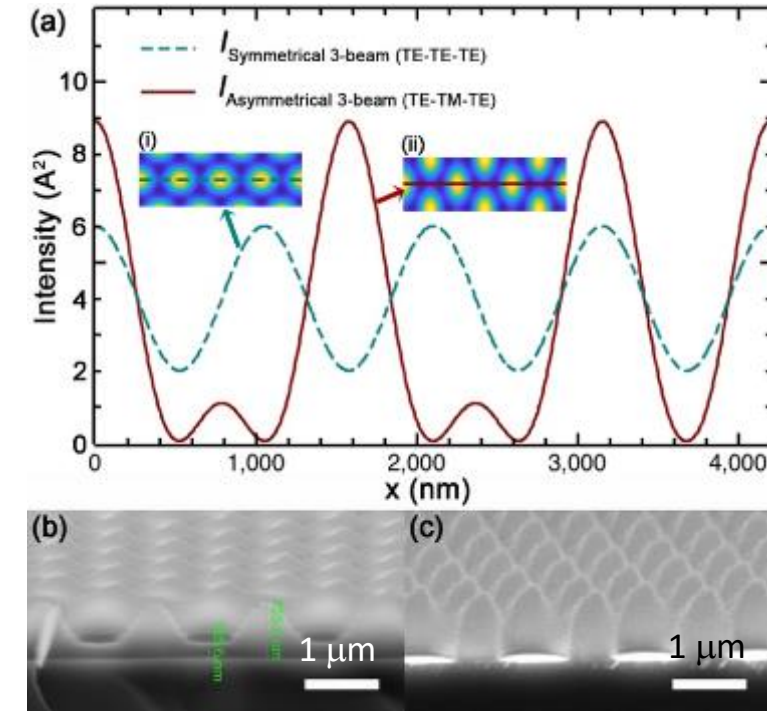


# Asymmetric three-beam LIL design and experimental examination

## Simulation results



Intensity simulation results (a-c) of the asymmetrical three-beam LIL with different polarization modes in the  $Z=0$  plane. (d) and (e) are the FFT frequency spectra of (a) and (b).



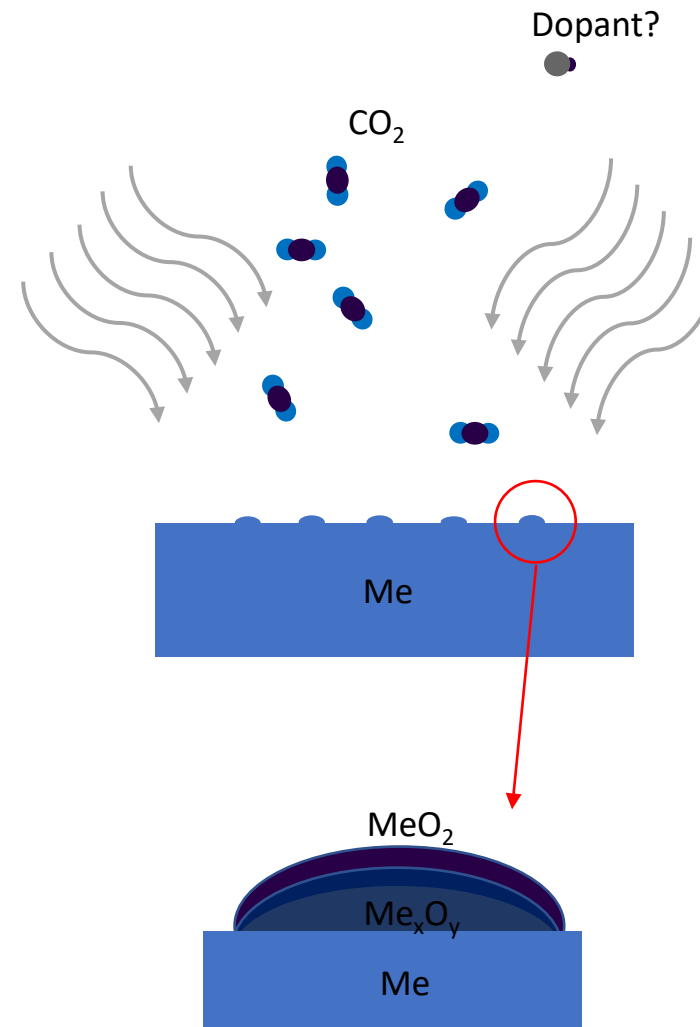
(a) Intensity curves along the corresponding lines in the insets that are optical patterns of the symmetrical three-beam LIL (i) and the asymmetrical three-beam LIL (ii); (b-c) SEM images of the photoresist samples that were generated at the same exposure dose, (b) and (c) correspond to (i) and (ii).

# Laser Interference Lithography in scCO<sub>2</sub>

**Tampere University**  
**Innolas**

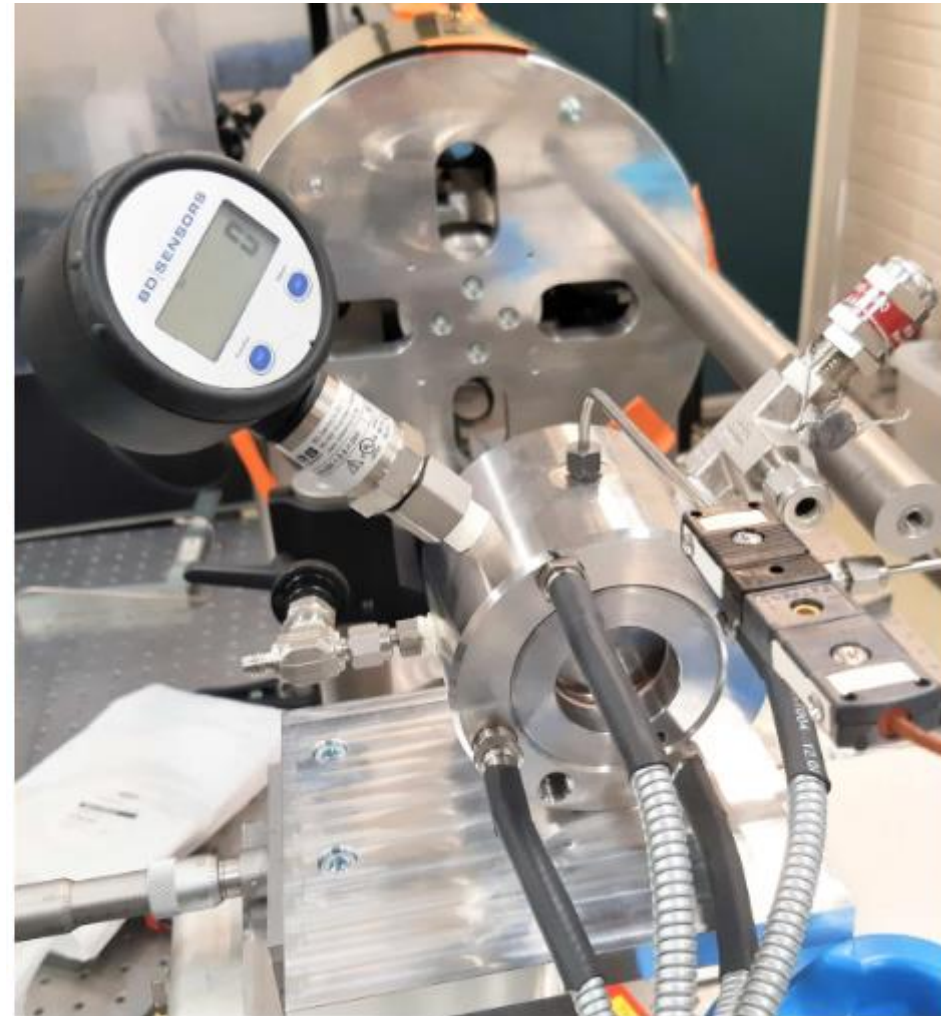
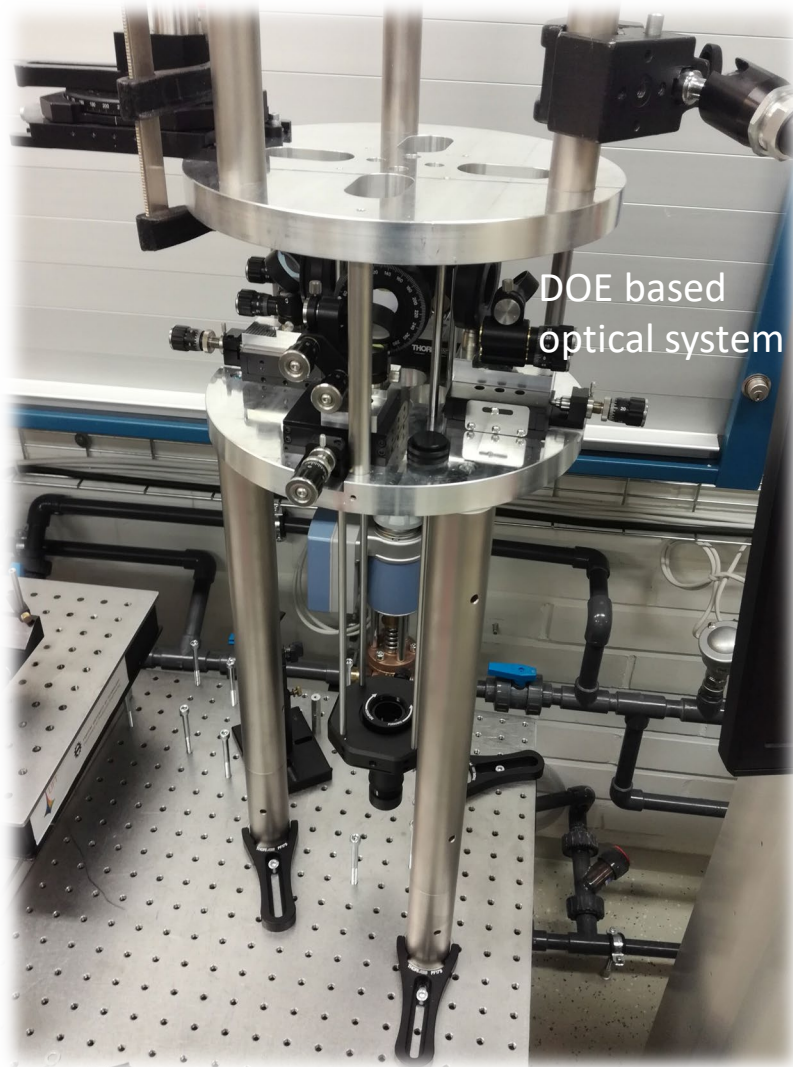
The approach uses super-critical CO<sub>2</sub> (>100 Bar) to achieve controllable localised oxidation of metal films, such as titanium, zinc etc. Local oxidation occurs only where the pulse(s) hits to substrate

Many parameters/variables need to be explored, including the laser pulse length, number of pulses, laser wavelength, CO<sub>2</sub> pressure etc



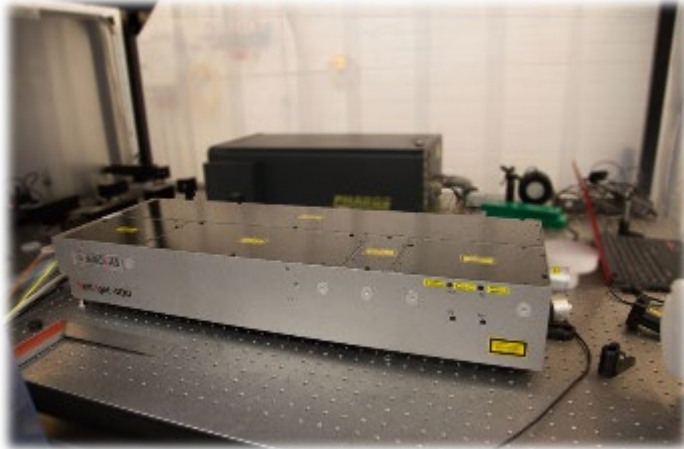


# SCCO<sub>2</sub> optical system and reaction pressure vessel



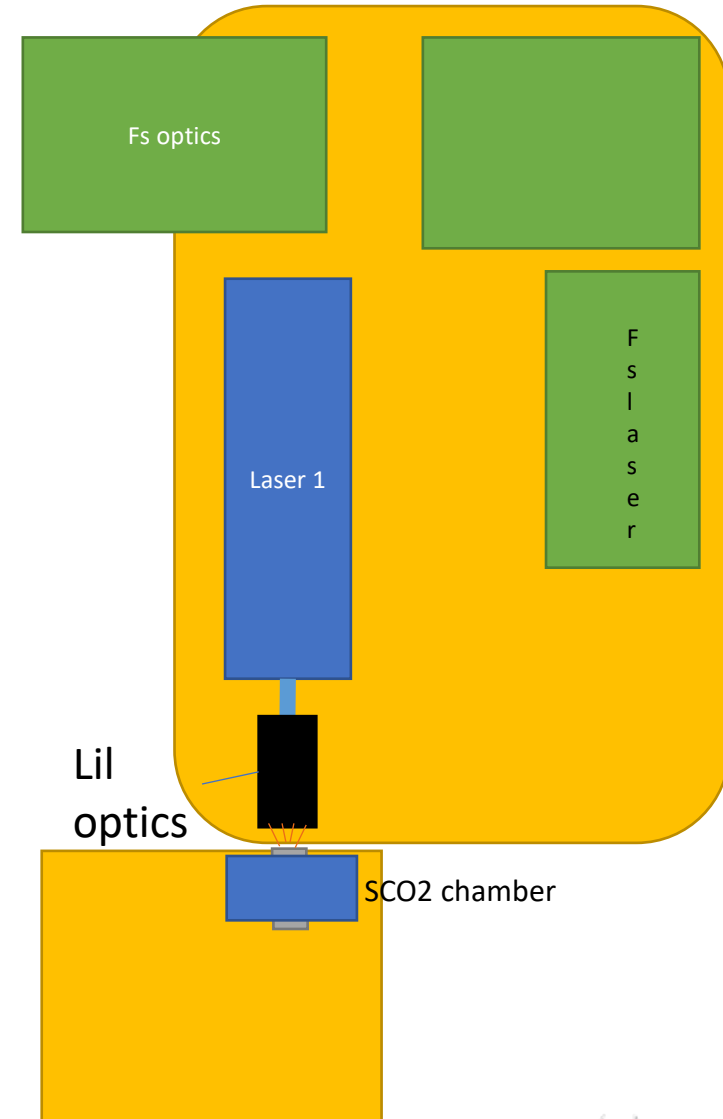
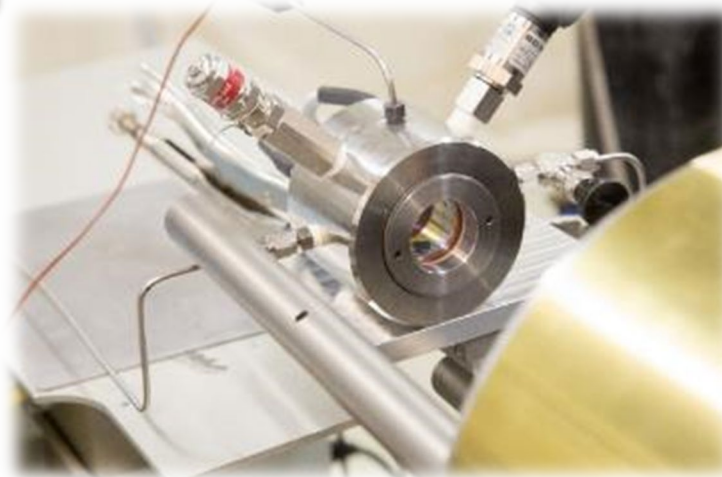
# Patterning in $\text{SCCO}_2$

Laser 1 is mounted on the large optical table along with the LIL system  
SCO<sub>2</sub> Chamber is next to the table on its own separate frame.



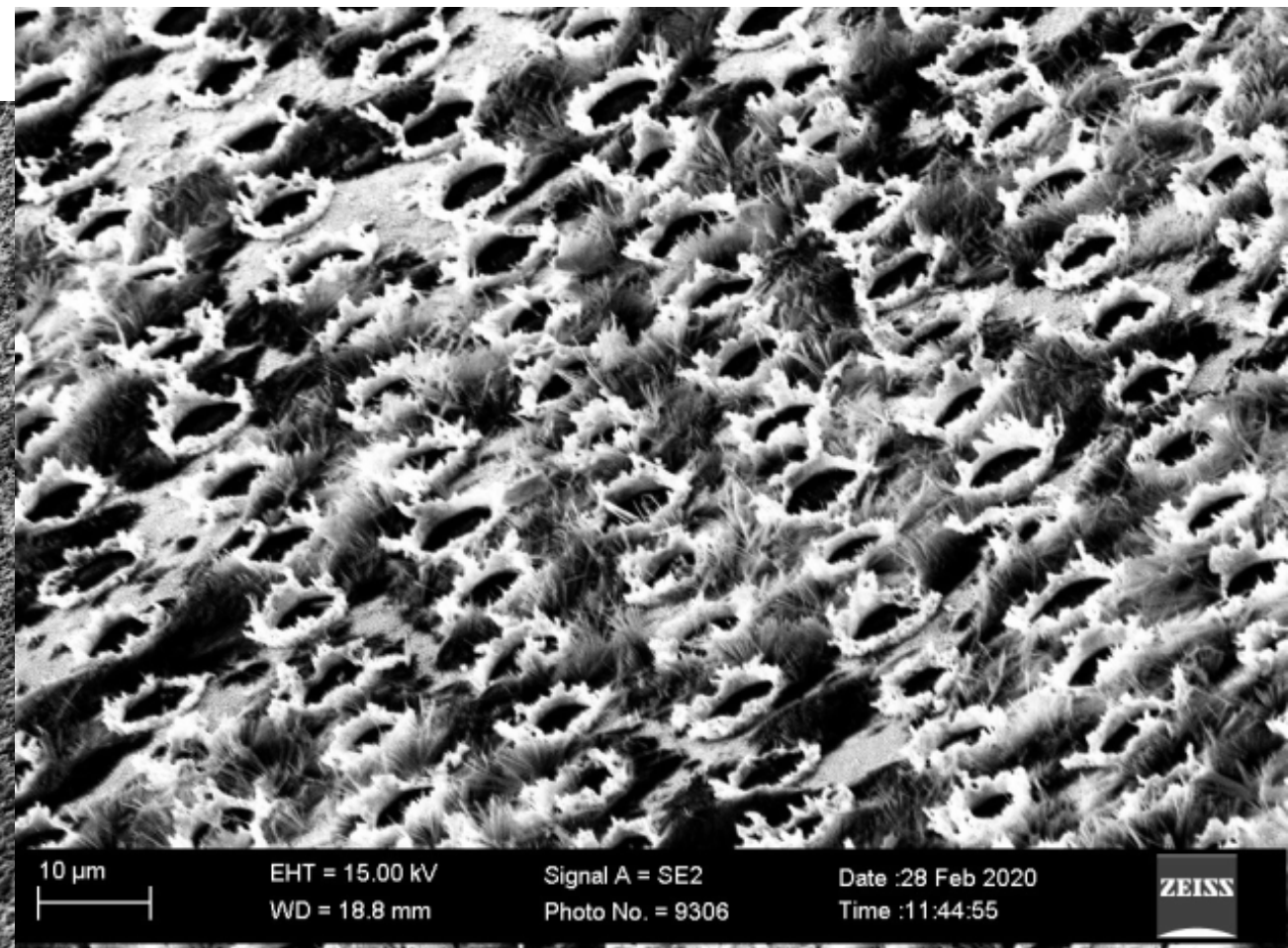
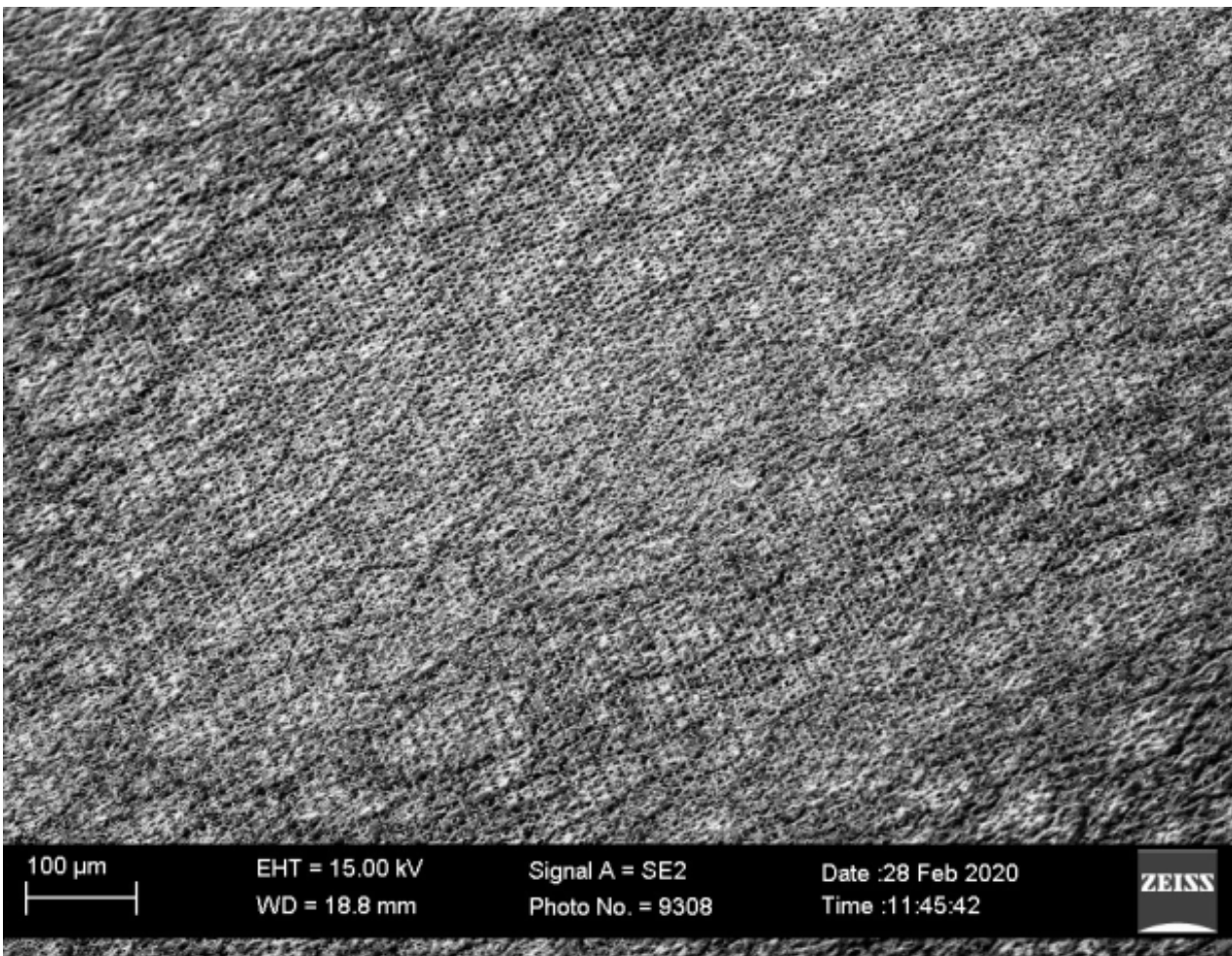
4 beams,  $0^\circ, 180^\circ, 90^\circ, 270^\circ$   
1064nm wavelength used  
~6mm beam diameter

New chamber with 34mm window was used



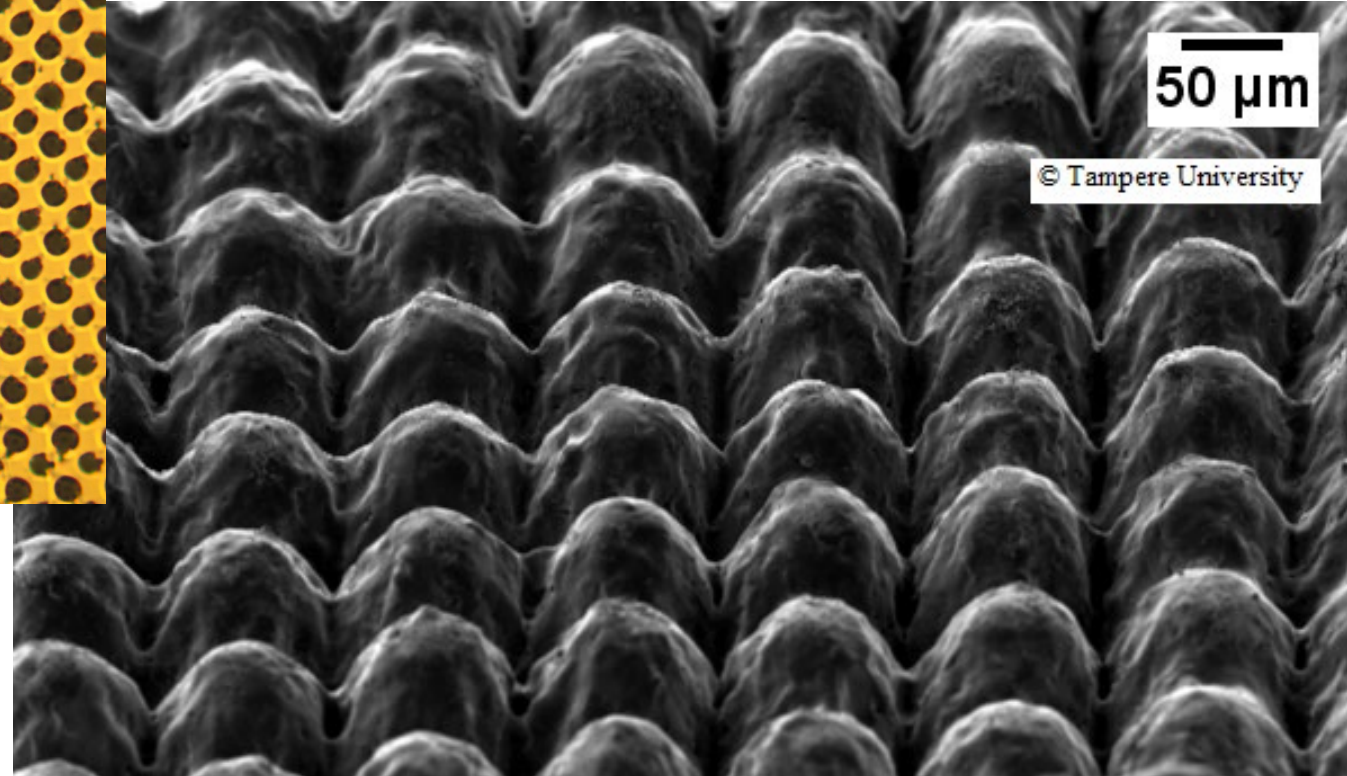
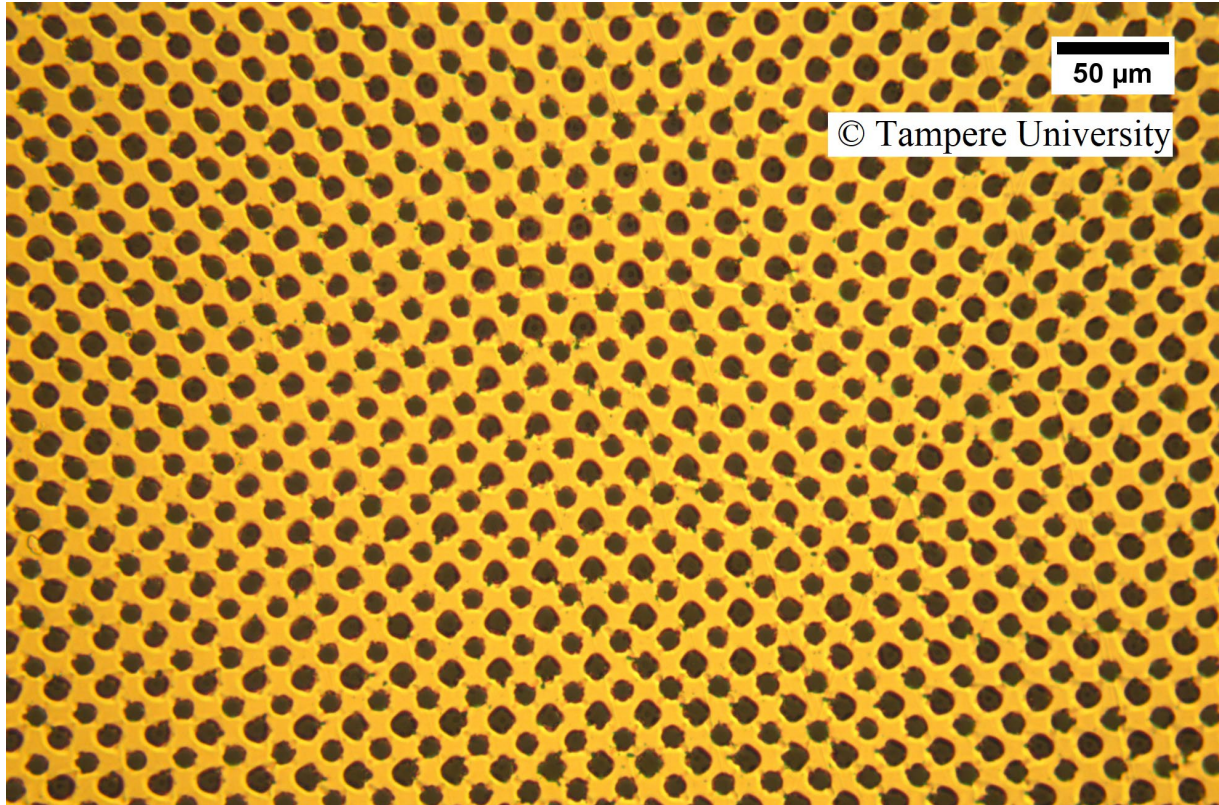


# LIL patterning of CO<sub>2</sub> treated Zn surfaces





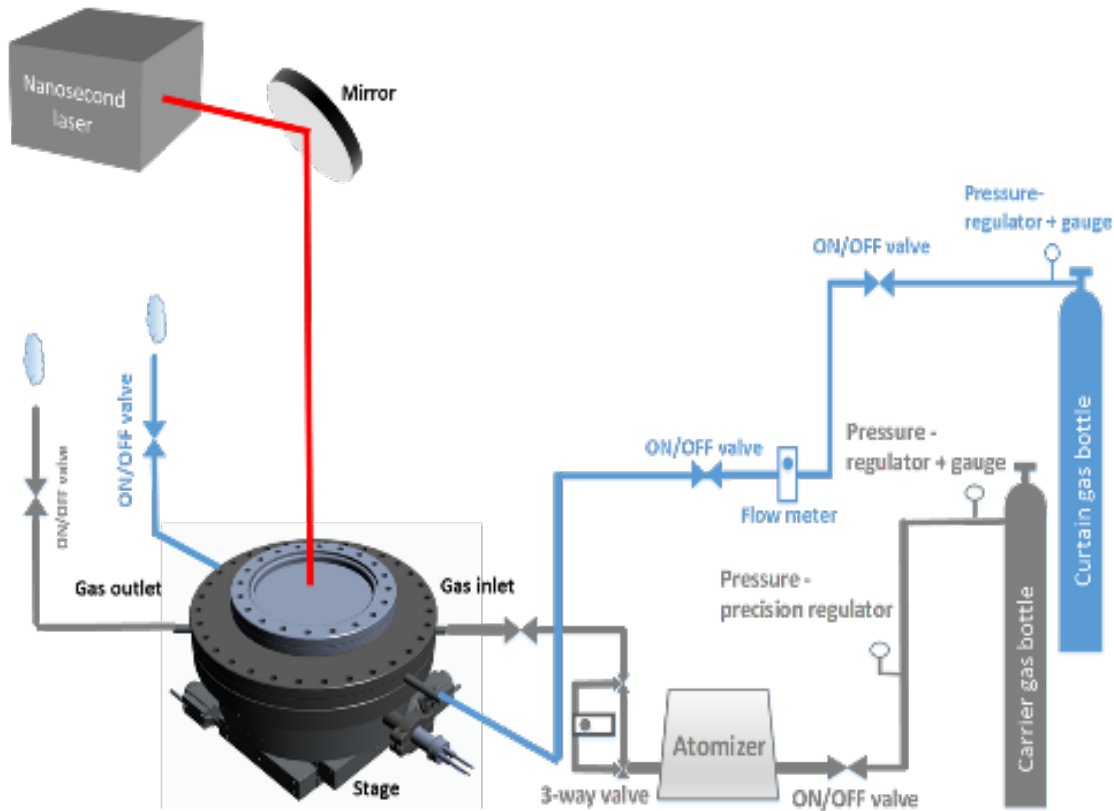
# Initial work on Titanium



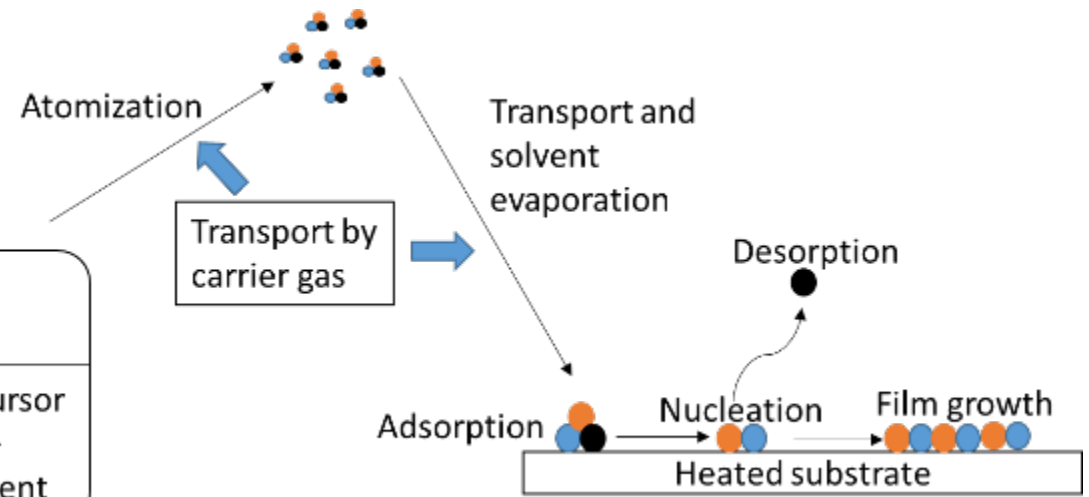
# Laser Interference Aerosol Assisted Chemical Vapor Deposition (LIAACVD)

**CEIT-IK4  
Innolas**

# Laser Enhanced Aerosol Assisted Chemical Vapor Deposition (LEAACVD)



**LEAACVD scheme**



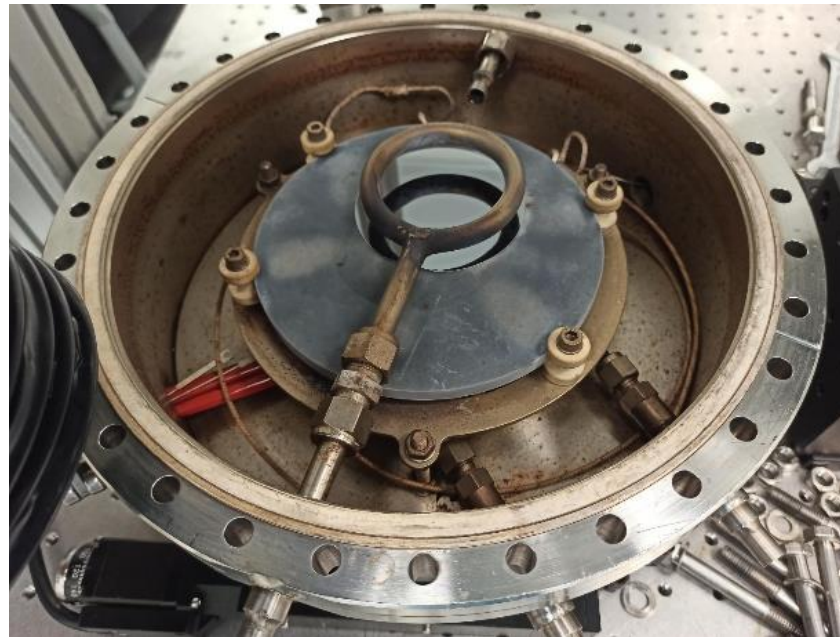
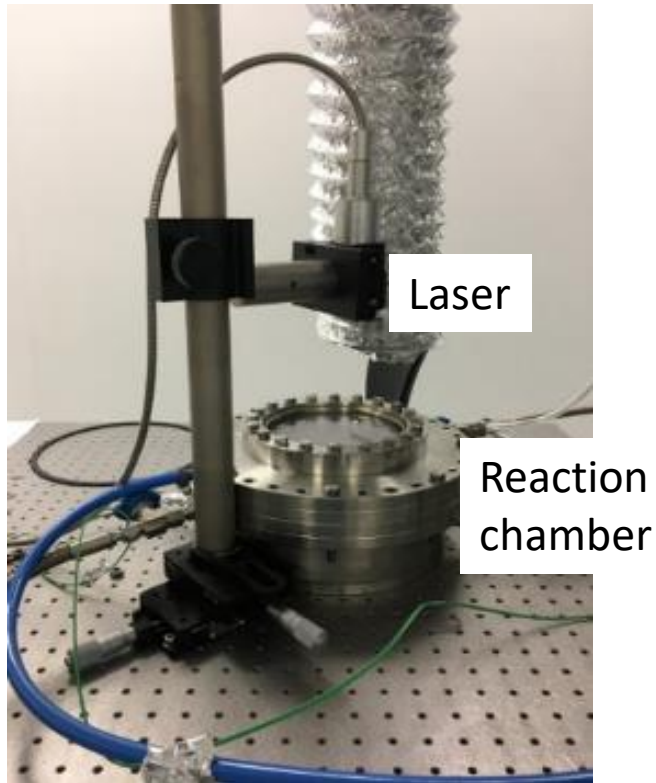
**Reaction scheme**

- Easy delivery and vaporization of a wide range of precursors.
- High deposition rate.
- Low pressure or atmospheric pressure.
- Good stoichiometric control of the reaction



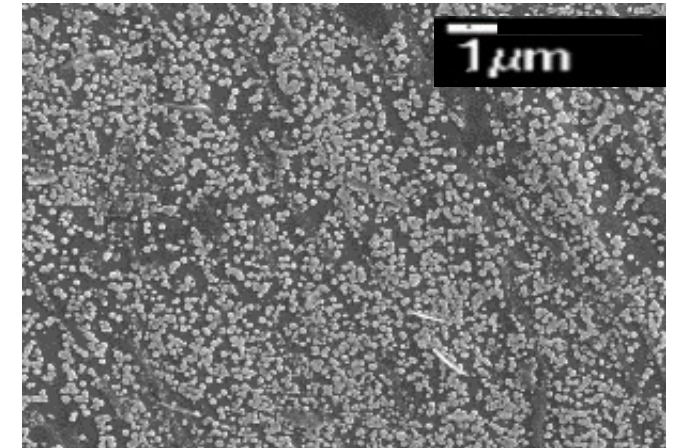
# Laser Enhanced Aerosol Assisted Chemical Vapor Deposition (LEAACVD)

## LEAACVD set-up



Reaction chamber

## LEAACVD results



$t=200\text{ ns}$   $T_{\text{heater}}=250\text{ }^{\circ}\text{C}$   
6l/min 5.5W 30 min

ZnO thin films grown by  
LEAACVD onto stainless  
steel substrates

# Laser Interference Aerosol Assisted Chemical Vapor Deposition (LIAACVD)

Maskless method to grow micro/nanostructured thin films

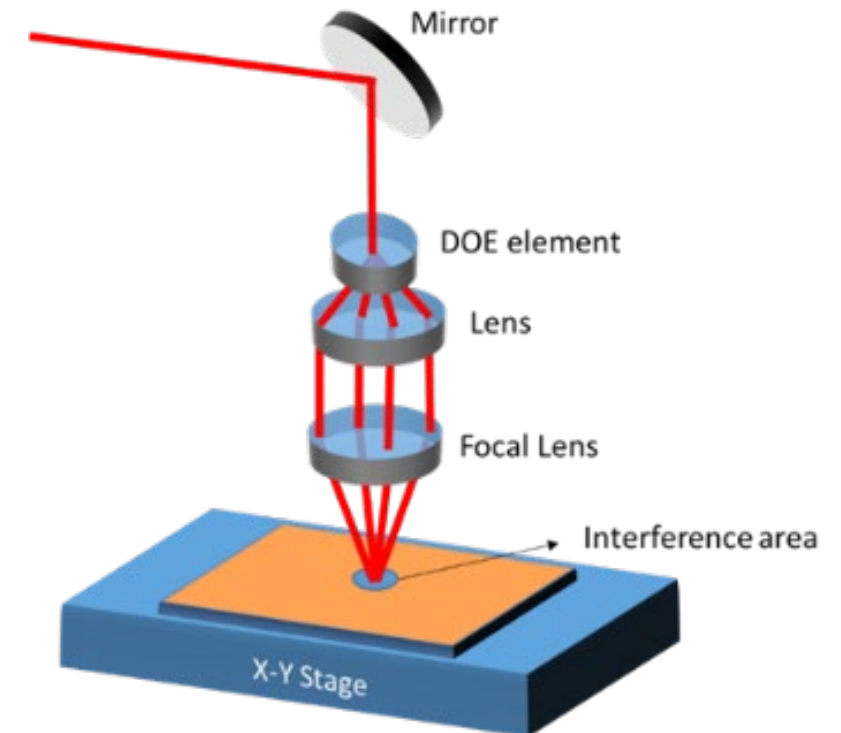
## Advantages:

- Direct writing with a laser interference pattern of structures with a resolution of  $1\ \mu\text{m}$
- Only the surface substrate is affected by the temperature deposition
- Geometry and tolerances are not influenced by high temperature conditions

## Disadvantages

- Low deposition rates

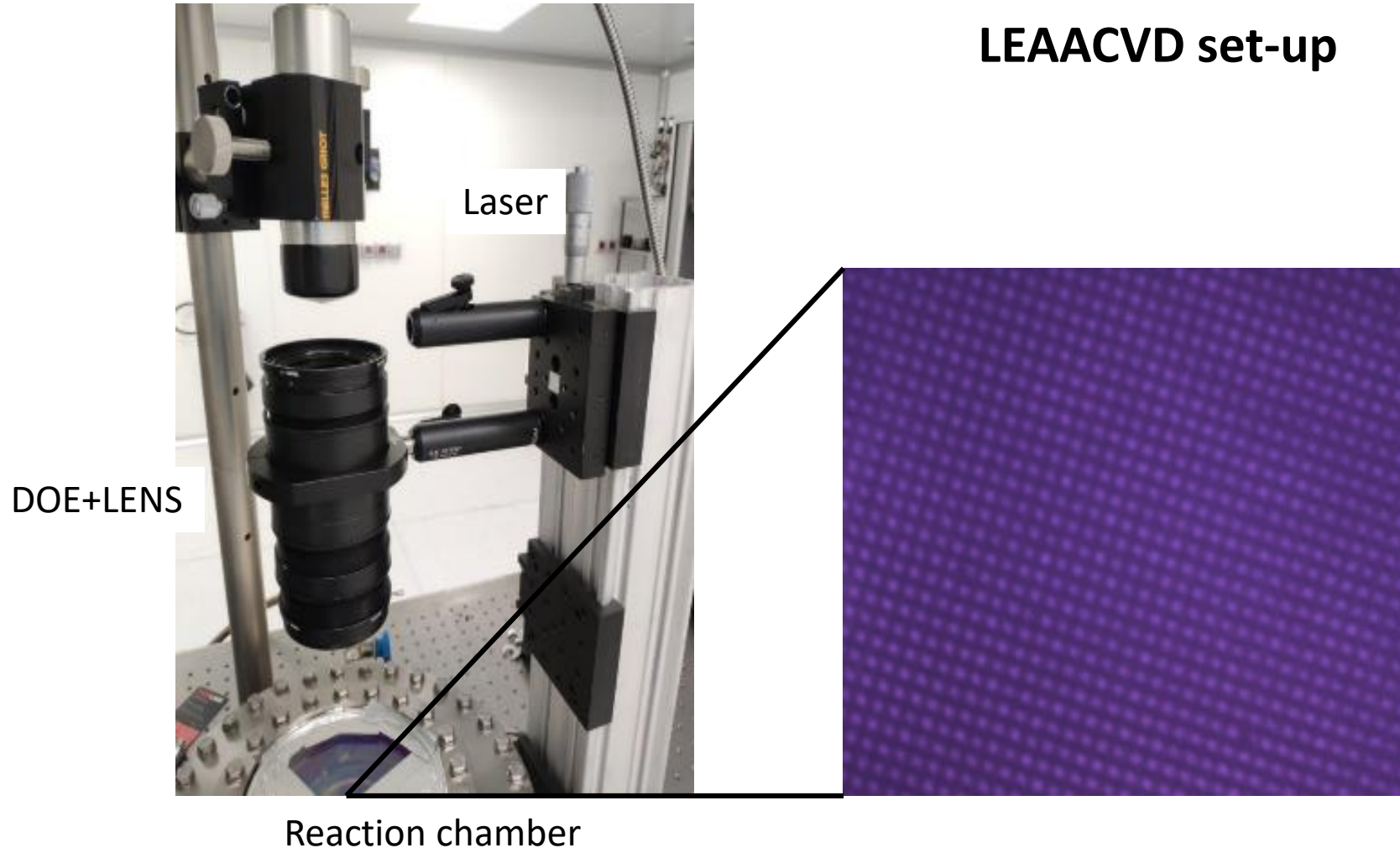
Set-up 3D



LIAACVD scheme

# Laser Interference Aerosol Assisted Chemical Vapor Deposition (LIAACVD)

LEAACVD set-up





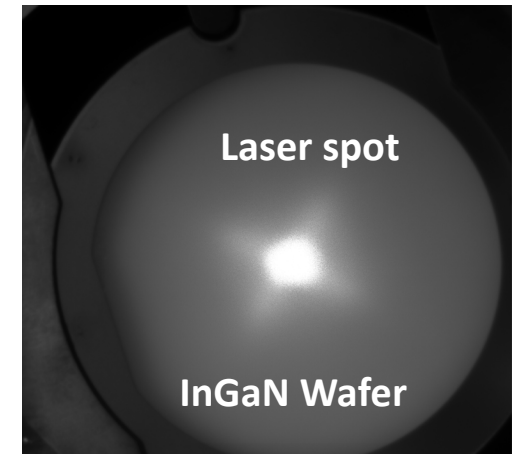
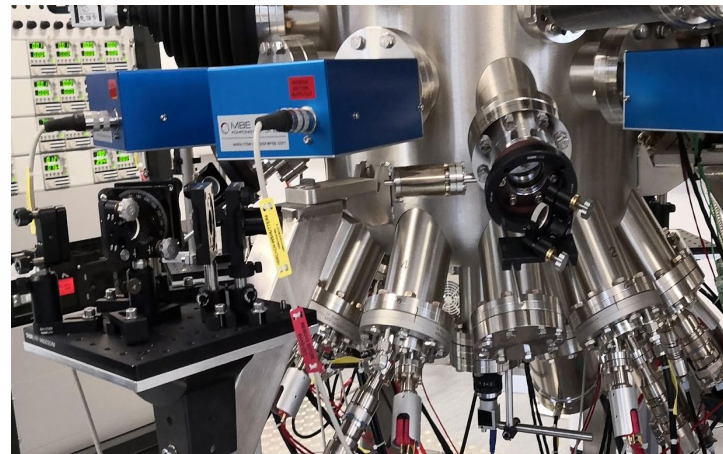
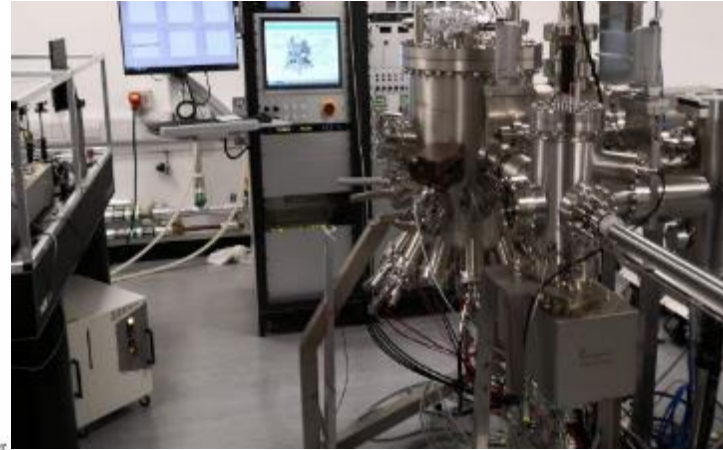
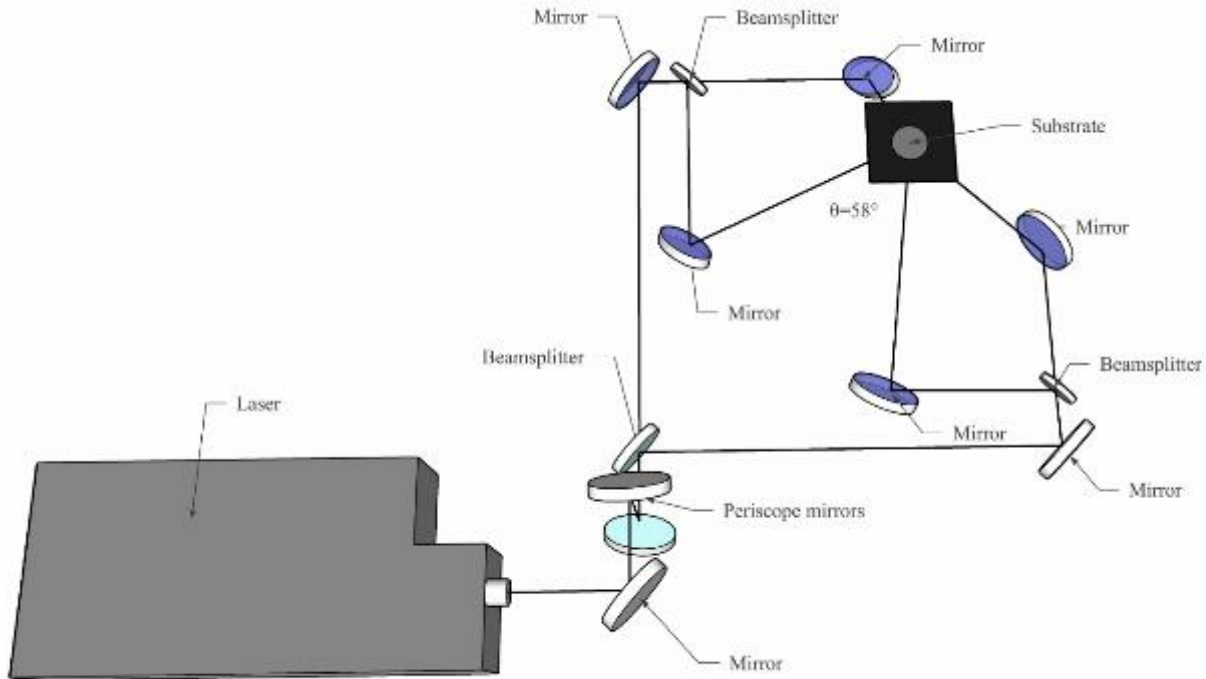
# MBE growth of III-V quantum dots

University of Sheffield

Innolas

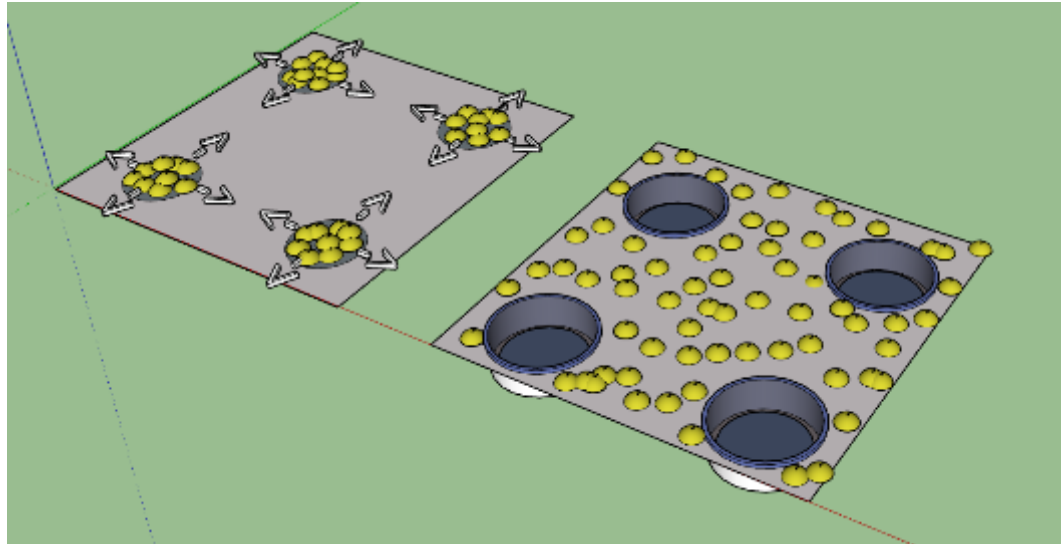
+ others

# MBE-LIP design and setup

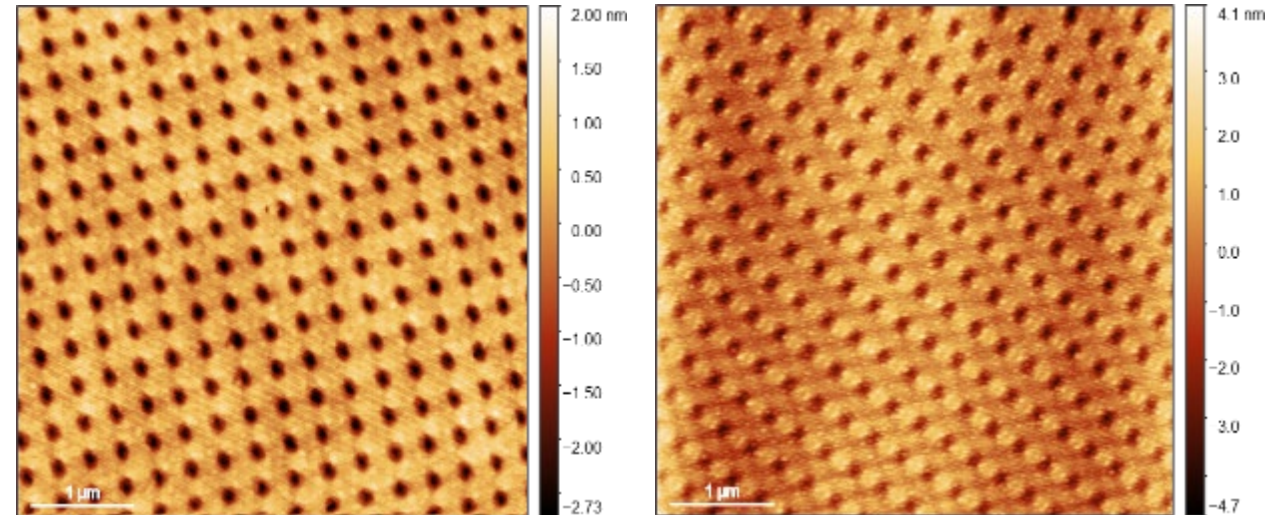


# Results - nanoholes

## ❖ Patterning on GaAs substrates



Towards the wafer center, where the beam overlap is the strongest (pulse energy  $\sim 30\text{-}50 \text{ mJ/cm}^2$ )



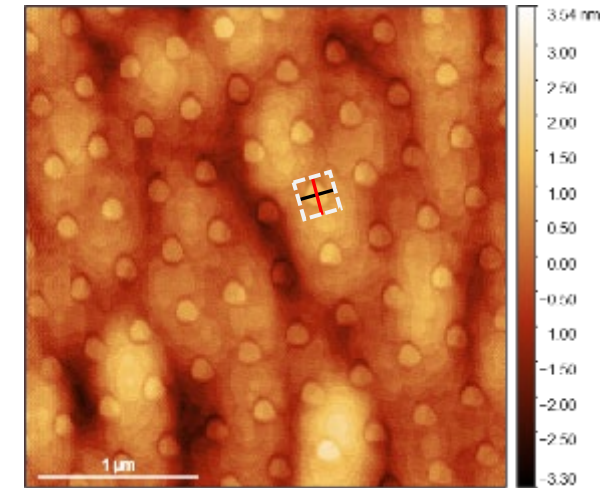
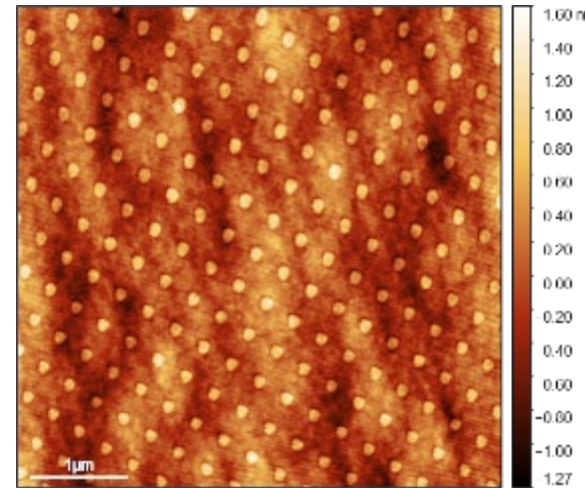
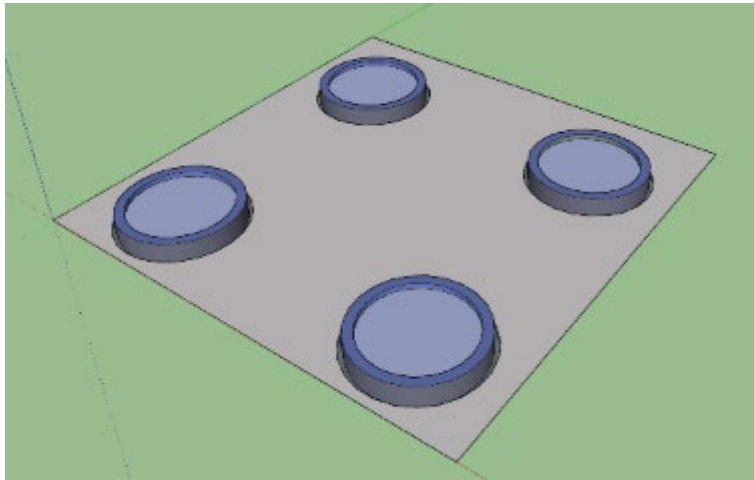
- Surface temperature  $>650^\circ\text{C}$
- Arsenic evaporation releasing free Ga
- Migration of Ga droplets to colder regions
- Etching of original surface
- GaAs nanoholes of 60-100nm wide and 2-4nm deep, 300nm pitch



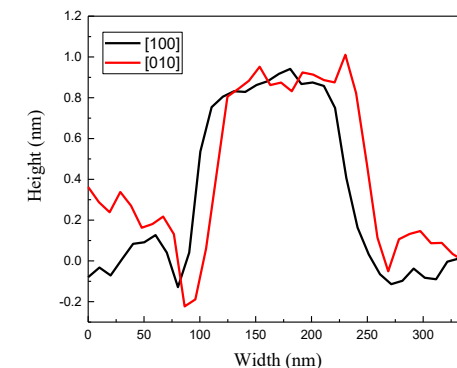
# Results - nanoislands

## ❖ Patterning on GaAs substrates

Towards the edges of the patterned region, where the beam overlap is lower (pulse energy 10-30 mJ/cm<sup>2</sup>)

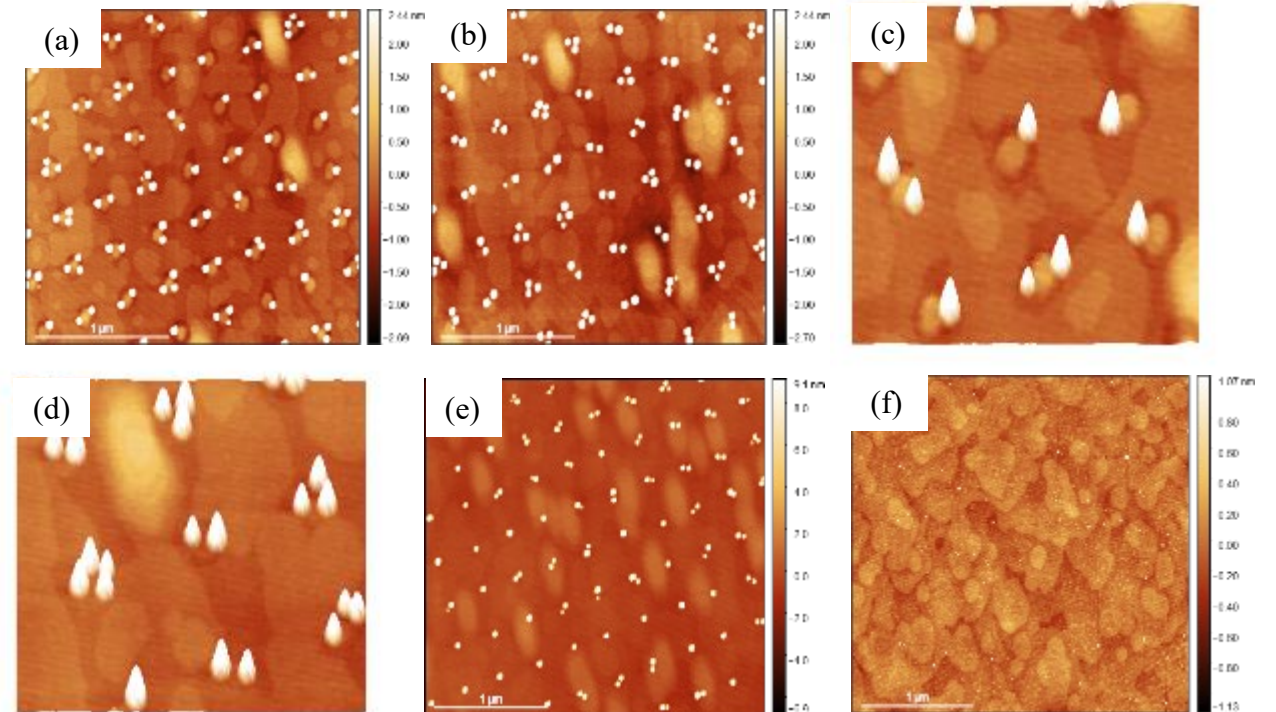
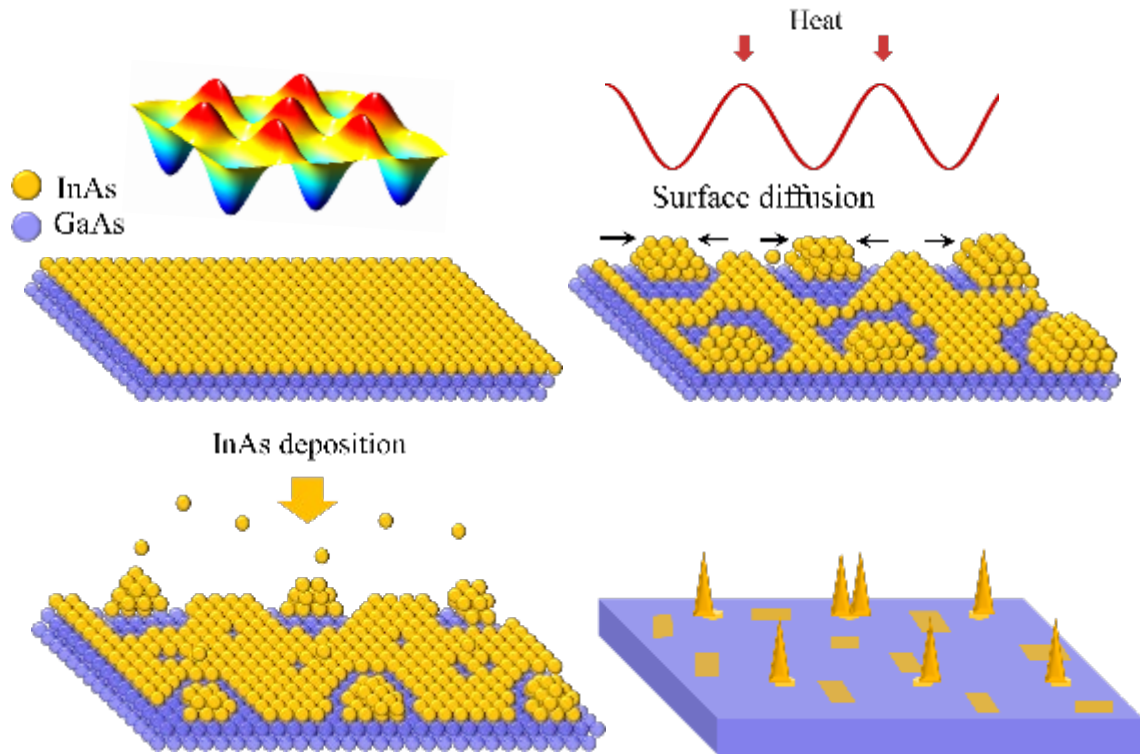


- No droplets, surface very flat apart from the ML islands
- GaAs nanoislands of 80-150nm wide and ~1nm (2-3 ML) high, 300nm pitch
- [Diffusion](#)-based mechanism. Ga atoms migrate from ‘hot’ region to ‘cold’ region



# Results - Nucleation of quantum dots

## ❖ Patterning on InAs/GaAs surfaces

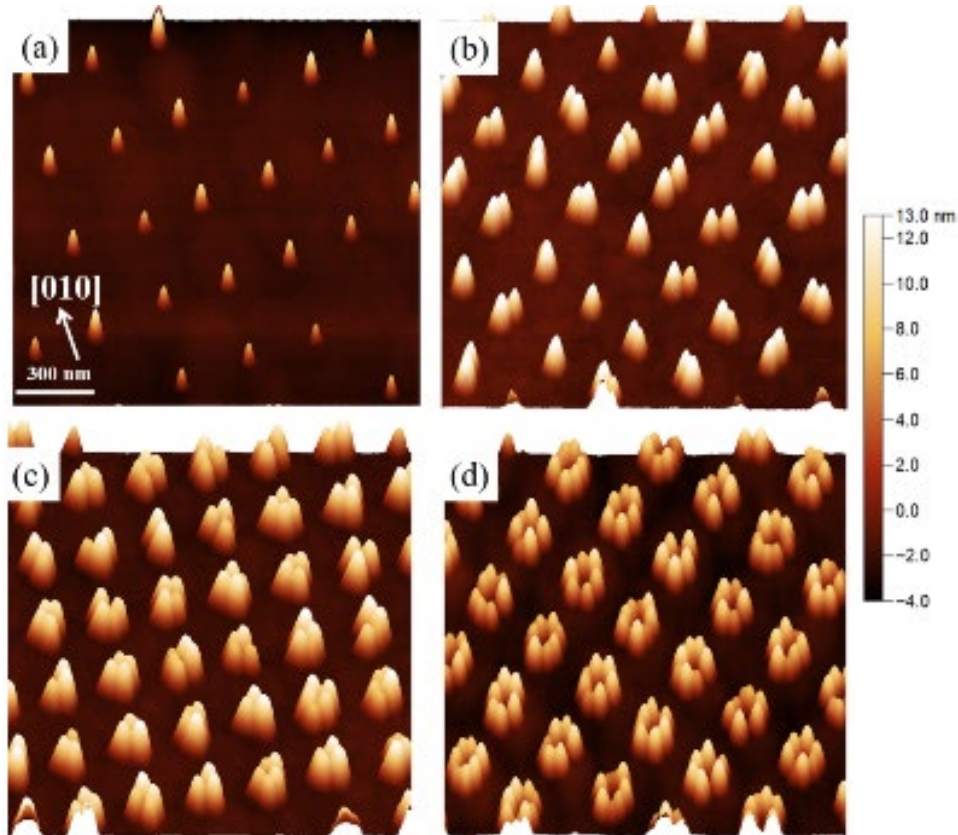


- InAs QDs prefer to nucleate at edge of small nanoislands
- Better uniformity than non-patterned QDs



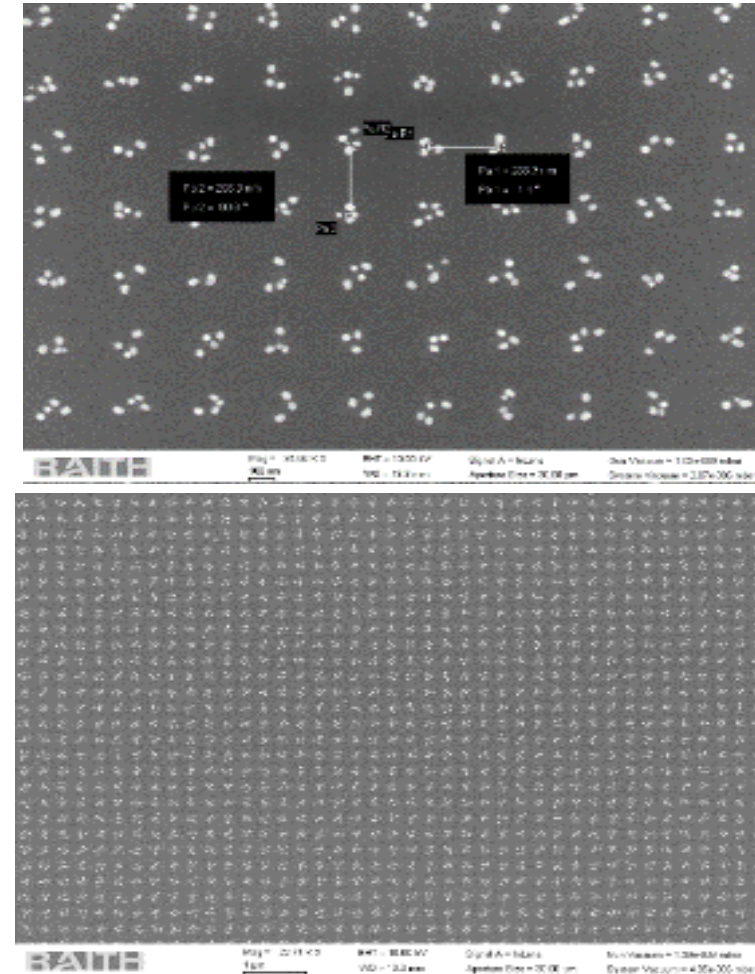
# Results – QD/QDM arrays

- ❖ Different InAs coverage of 1.55 ML, 1.6 ML, 1.65 ML, 1.75 ML



With careful control we can achieve one or more quantum dots per site.

- ❖ GaAs droplet epitaxy on Silicon:





# Pulsed Lasers for interference lithography

Innolas Laser  
+ others

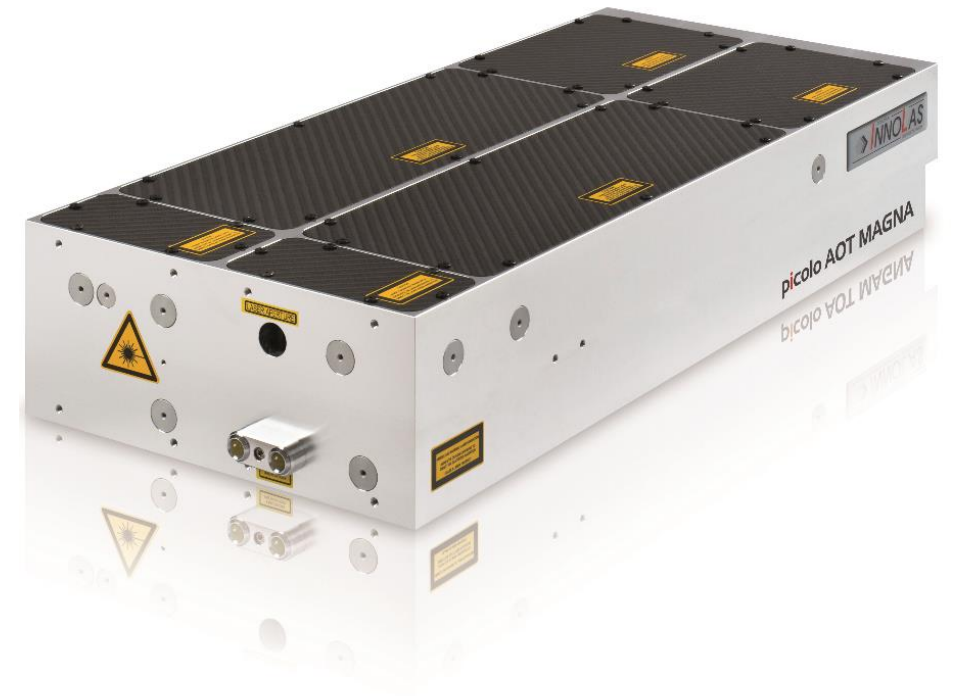
# Laser Development (example)

## Standard Specifications in use for MBE and the scCO<sub>2</sub> work)

- 1064 nm + 532 nm + 355 nm (priority)
- Pulse duration: 5-7ns
- Repetition: 10Hz
- Polarisation: Linear >100:1
- Bandwidth: As low as possible (injection seeding)
- Energy ~ 100mJ at 355nm

## Areas to improve

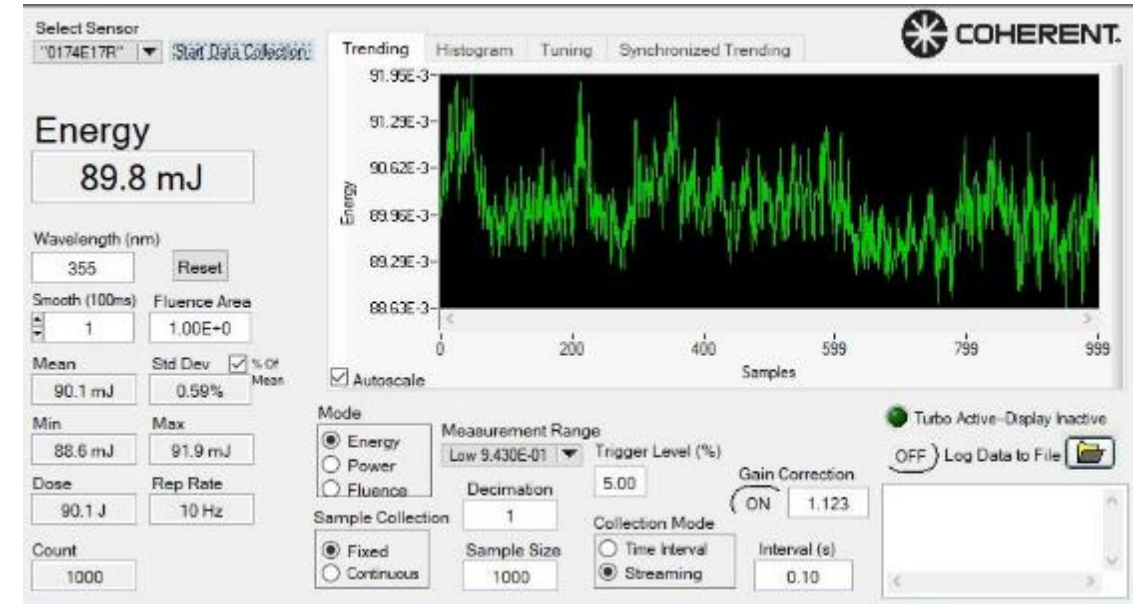
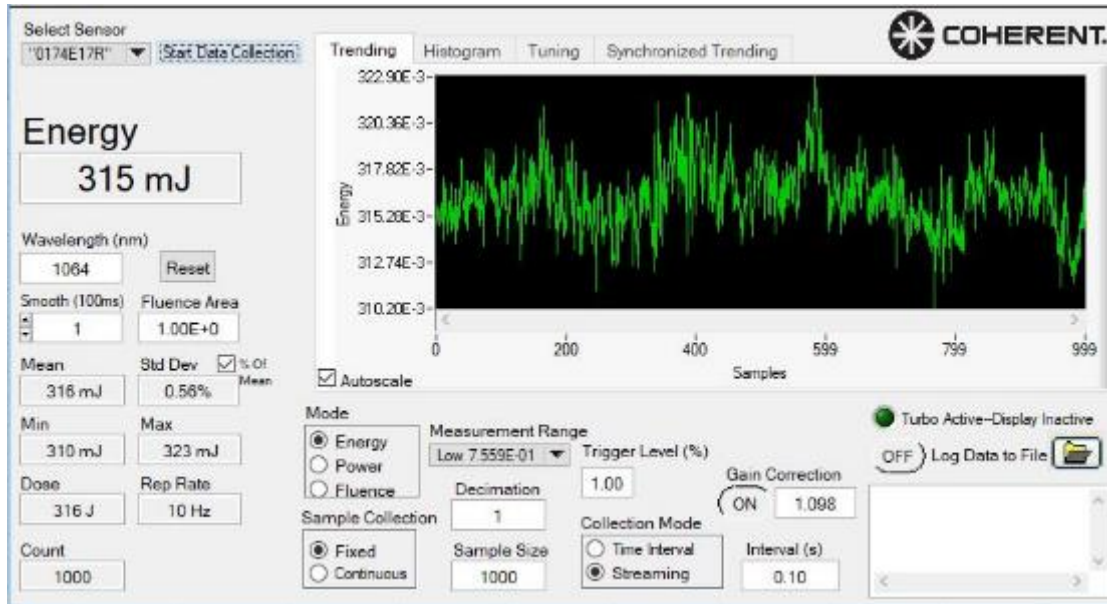
- Energy stability
- Beam profile
- Wavefront
- Coherence



# Performance – Energy / Stability

@1064 nm: <0.6% RMS (below specs 0.7%)

@355 nm: <0.6% RMS (below specs 0.7%)

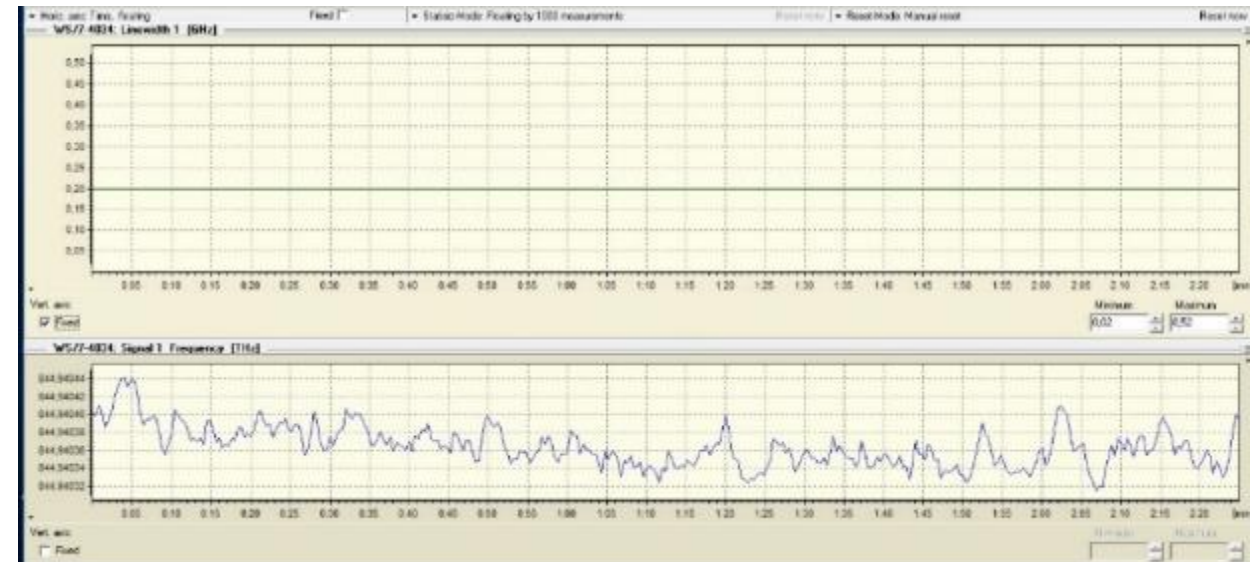
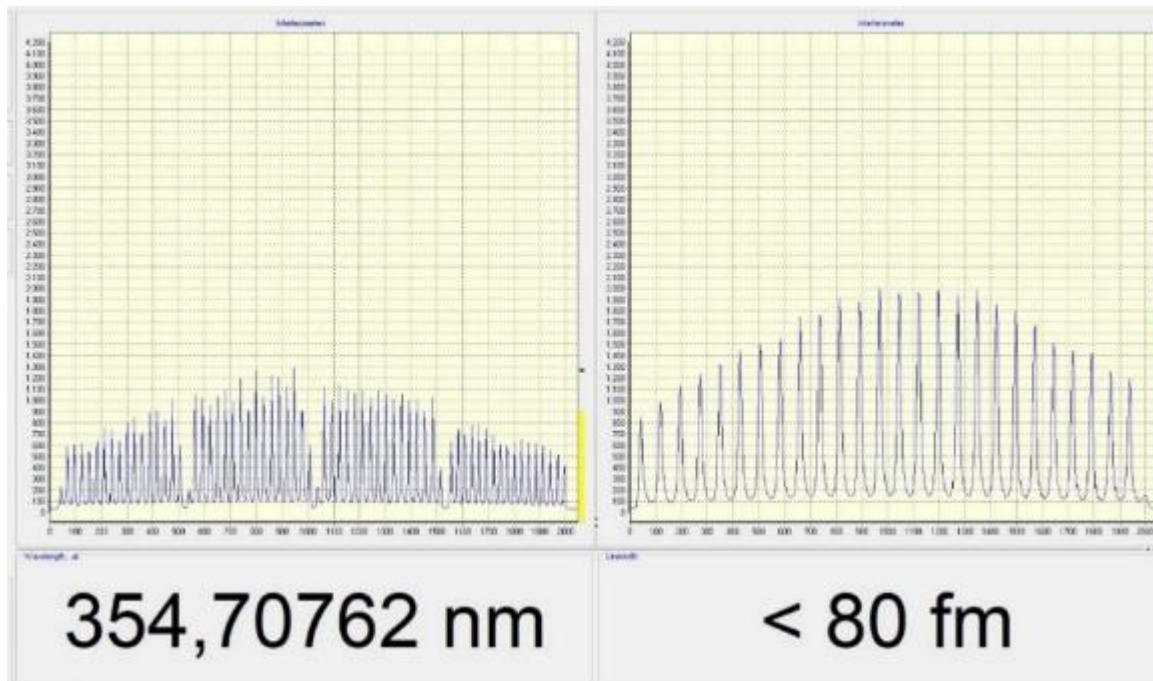




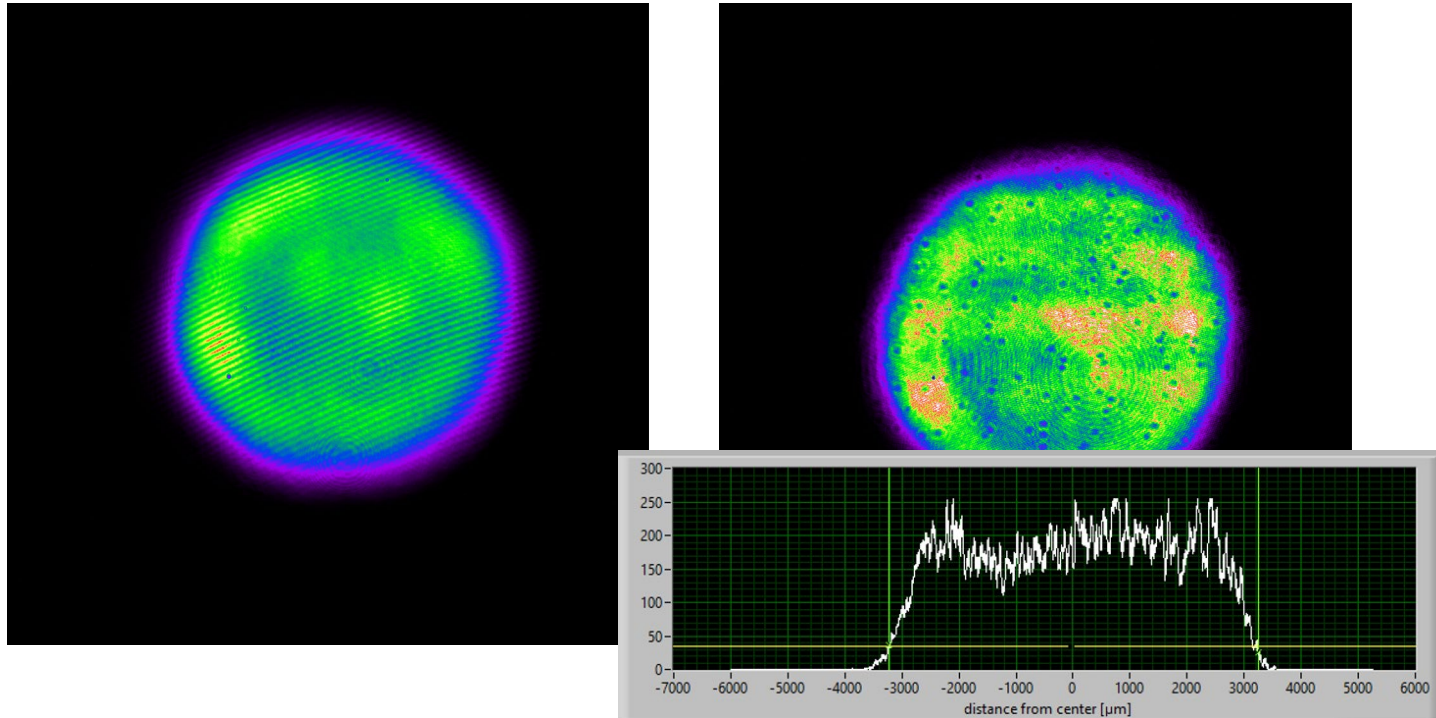
# Performance – Coherence

355 nm:

$\Delta\lambda = \ll 80 \text{ fm}$ ;  $\Delta f = \ll 200 \text{ MHz}$   $\rightarrow$  Coherence Length  $\gg 1.2 \text{ meter}$

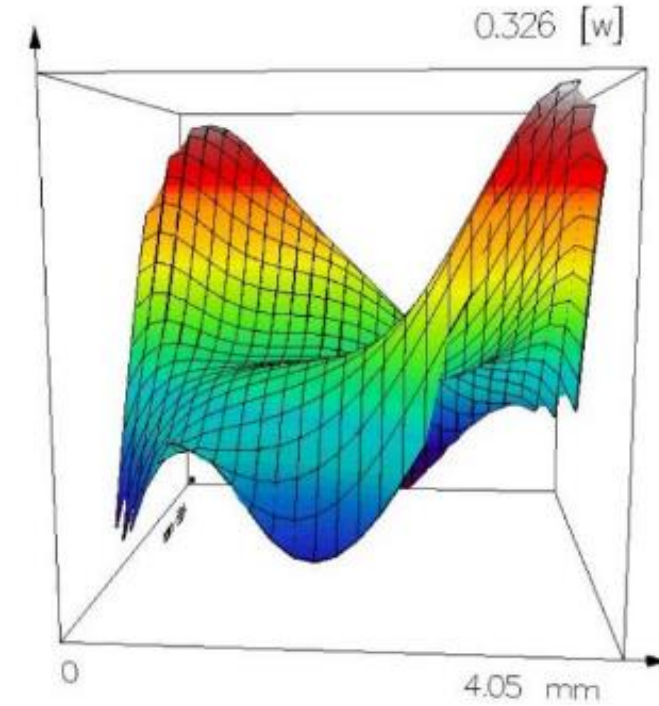


# Performance – Beam profile and wavefront



1064 nm Near field

355 nm Near field



355 nm Near Field  
 $P-V = 0.3 \lambda$

# Thank you for listening

More detailed talks follow later today

13:30

Interference Patterning

Session 36: Interference Patterning II

🕒 Session starts at 13:10

Lecture

**In-situ pulsed laser interference patterning for quantum dot site control**

**Prof. Mark Hopkinson** Yunran Wang Dr. Im Sik Han Dr. Chaoyuan Jin Dr. Santiago Olaizola Dr. Dayou Li Prof. Changsi Peng Dr. Andreas Börner Prof. Erkki Levanen

📍 Room 2

14:30

Interference Patterning

Session 36: Interference Patterning II

🕒 Session starts at 13:10

Lecture

🎓 Student **LIL system for pressurized environment processing**

**Tero Kumpulainen** Amandeep Singh Nelli Palmu Arnold Ismailov Andreas Börner Hani Abou Hadba Jorma Vihinen Erkki Levanen

📍 Room 2

Please feel free to talk with us at the Innolas stand

Or you may contact me at [m.hopkinson@sheffield.ac.uk](mailto:m.hopkinson@sheffield.ac.uk)